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Ø

Sign in FA TS Sign in Sign in

1 Please sign in	
Username	
Password	CIM.AS
Sign in	

To sign in, enter provided username and password and press the 'Sign in' button. When signed in the Dashboard page is presented.



1 Main menu

The FACTS main menu line is placed at the top of the page.

FACTS	Dashboard	Reports	System	Administrator -
About				0

The above menu is taken from the reports / SPC page. This is indicated by 'gray' area. This area shows the actual page. You can click in the gray area to shortcut back in the menu.

To select a main menu item, simply click the text in in the green area.

1.1 Menu items

FACTS – Opens info page about FACTS, including build version etc.
Dashboard – Opens the Dashboard page
Reports – Opens the main report page
System – Opens the system main page
Question mark – Opens the user manual

Remark

Depending of the assigned user rights some menu items will not be available.



2 Dashboard

To enter Dashboard, click the 'Dashboard' text in menu line.

FACTS Dashboard Reports System

Administrator -

The Dashboard shows the performance of the test data by providing a top 15 of 'Most Tested' and 'Worst Yield' tests.

K Most Tested C ∨ K Most Tested C ∨ K Most Tested Vield Item Test Yield Item Test SP 3501/15/2000 Vacuum Test SP 3501/201/2000 Vacuum Test SP 3501/201/2000 Vacuum Test SP 3501/201/2000 Vacuum Test SP 3501/201/201/2000 Vacuum Test SP 3500/201/201/2000 Vacuum Test SP 3500/201/201/200/200/200/200/200/200/200/2	hb ash	board								
Item Test Yeld 0000-042 - DEIF DEIF DEIF (den med bow) Dolphin_HS_ALL_RevS 4£1 459 (95, 44) 0 Tf52-35x Vacuum Tranceiver test - SP 3510/15/20/60 Vacuumtest Sp35xx Transceiver Vacuum Test 364 304 (83, 54) 0 Tf52-35x Vacuum Tranceiver test - SP 3510/15/20/60 Vacuumtest Sp12350 Charger Module 224 223 (84, 55) 0 Tf59-1235XX (SP3510/20) - SP35xx Sp35xx Module Test 246 140 (56, 54) 0 Tf59-1235XX (SP3510/20) - SP35xx Sp35xx Module Test 246 140 (56, 54) 0 Tf59-1235X3 - gammel Инструменты fest Sp35xx Module Test 246 140 (56, 64) 0 Tf59-1235X3 - gammel Инструменты fest Sp35xx Module Test 246 140 (56, 7129749 - Mini-C 2G MB Mini-C Mainboard function Test 216 95 (44) 0 Tf59-1235X3 - gammel Инструменты fest Sp35xx Module Test 246 140 (57, 43) (57, 129749 - Mini-C 2G MB Mini-C Mainboard function Test 146 71 (41) 0 Tf59-1235XX (Sp350	N	flost Tested			C 🗸	* 1	Worst Yield			ŝ
 10000-042 - DEIF DEIF [den med bavl) 10000-042 - DEIF DEIF [den med bavl) 11000-042 - DEIF DEIF [den med bavl) 11000-042 - DEIF DEIF [den med bavl) 11100-1255xX acuum Tranceiver tabvel SP 3510/15/20/60 Vacuum test SP 3510/15/20/60 Vacuum test SP 3510/15/20/60/60/60/60/60/60/60/60/60/60/60/60/60		Item	Test	Tests	Yield		Item	Test	Tests	Yie
Q Tr52-35xx Vacuum Tranceiver test - SP 3510/15/20/60 Vacuumtest SP 35xx Transceiver Vacuum Test 364 304 (83, 54) Q 59-123950 · Single charger module 58-123950 · Charger Module 264 223 (84, 58) Q Tr59-1208K4 · E700 Mainboard Explorer 700 Motherboard 245 140 (56, 58) Q Tr59-1208K4 · E700 Mainboard Explorer 700 Motherboard 245 166 (43, 38) Q Tr59-1235XX [SP3510/20] · SP35xx SP35xx Module Test 245 166 (43, 38) Q Tr59-1208K4 · E700 Mainboard Explorer 700 Motherboard 245 166 (43, 38) Q Tr59-1205XX [SP3510/20] · SP35xx SP35xx Module Test 216 95 (44, 08) Q Tr59-1235X3 · gammel / Mcrpy Memmel test SP35xx Module Test 216 95 (44, 08) Q Tr59-1235XX [SP3510/20] · SP35x SP35xx Module Test 216 95 (44, 08) Q Tr59-1235XX [SP3510/20] · SP35x SP35xx Module Test 216 95 (44, 08) Q Tr59-1235XX [SP3510/20] · SP35x SP35xx Module Test 216 95 (44, 08) </td <td>୍</td> <td>10000-042 - DEIF DEIF DEIF (den med bøvl)</td> <td>Dolphin_HS_ALL_RevS</td> <td>481</td> <td>459 (95,4%)</td> <td>ଭ୍</td> <td>57-129748 - Mini-C 2G LNA/HPA</td> <td>TT3027A HPA-LNA PCB test</td> <td>126</td> <td>52 (41,34</td>	୍	10000-042 - DEIF DEIF DEIF (den med bøvl)	Dolphin_HS_ALL_RevS	481	459 (95,4%)	ଭ୍	57-129748 - Mini-C 2G LNA/HPA	TT3027A HPA-LNA PCB test	126	52 (41,34
a 59-123950 - Single charger module 58-123950 Charger Module 264 223 (24, 54) a T59-1235XX[SP3510/20] - SP35xx SP35xx Module Test 24e 140 (56, 58) a TT59-1236X4(SP3510/20] - SP35xx SP35xx Module Test 24e 140 (56, 58) a TT59-120864 - E700 Mainboard Explorer 700 Motherboard 24f 106 (43, 38) a VHF Battery Vacuum test - Vacuum SP35xx Battery Vacuum 22f 198 (88, 08) a TT59-120533 - gammel Инструменты SP35xx Module Test 21e 95 (44, 08) a TT59-120533 - gammel Инструменты SP35xx Module Test 209 112 (53, 64) a TT59-120533 - gammel Инструменты SP35xx Module Test 209 112 (53, 64) a TT69-1235XX - SP3500 Display Test 174 145 (83, 38) TT57-124571 - BGAN-X HPA BGAN-X Generic Mainboard Main Unit 107 68 62-130933 - VHF6000 Adv Main unit VHF6000 Adv Main Unit 107 68 66 a TT67-124574 - Thrane IP Handset, Wired Maritime VoIP Handset 169 122 </td <td>ର୍</td> <td>TT62-35xx Vacuum Tranceiver test - SP 3510/15/20/60 Vacuumtest</td> <td>SP35xx Transceiver Vacuum Test</td> <td>364</td> <td>304 (83,5%)</td> <td>ଭ୍</td> <td>TT59-120864 - E700 Mainboard</td> <td>Explorer 700 Motherboard</td> <td>245</td> <td>106 (43,39</td>	ର୍	TT62-35xx Vacuum Tranceiver test - SP 3510/15/20/60 Vacuumtest	SP35xx Transceiver Vacuum Test	364	304 (83,5%)	ଭ୍	TT59-120864 - E700 Mainboard	Explorer 700 Motherboard	245	106 (43,39
a) TT59-1235X1[SP3510/20] - SP35XX SP35XX Module Test 242 140 (56, 5%) a) TT59-120864 - E700 Mainboard Explorer 700 Motherboard 245 106 (43, 3%) b) TT59-120864 - E700 Mainboard SP35XX Module Test 216 95 (44, 0%) c) TT59-120864 - E700 Mainboard SP35XX Module Test 216 95 (44, 0%) c) TT59-123533 - gammel Инструменты SP35XX Module Test 216 95 (44, 0%) c) TT59-123533 - gammel Инструменты SP35XX Module Test 216 95 (44, 0%) c) TT59-123533 - gammel Инструменты SP35XX Module Test 216 95 (44, 0%) c) TT59-123533 - gammel Инструменты SP35XX Module Test 209 112 (53, 6%) c) TT60-1235XX - SP3500 Display Test SP35XX AfteX Transceiver 171 131 (76, 6%) c) TT57-124571 - BGAN-X HPA BGAN-X Generic Mainboard Function Test 148 71 (48, 0%) c) TT57-12450 - Bgan-X BDU Mainboard Maritime VoIP Handset 169 122 (72, 2%) c) TT57-124570 - Thrane IP Handset, Wired Maritime VoIP Handset 161 135 (83, 9%) c)	ଭ୍	59-123950 - Single charger module	58-123950 Charger Module	264	223 (84,5%)	ଭ୍	57-129749 - Mini-C 2G MB	Mini-C Mainboard Function Test (-Noise)	128	56 (43,8%
a. T159-120864 - E700 Mainboard Explorer 700 Motherboard 245 106 (43,38) b. WHE Battery Vacuum test - Vacuum SP35xx Battery Vacuum 225 198 (88,08) c. T159-123533 - gammel Инструменты SP35xx Module Test 216 95 (44,08) a. T159-123533 - gammel Инструменты SP35xx Module Test 216 95 (44,08) a. 403504A - Atex Battery Secundary 403504A Final Test 209 112 (53,68) a. T150-1235XX - SP3500 Display Test SP35xx Attex Transceiver 171 131 (76,68) a. T152-35XX[623520A SP3520 VHF, Vacuum Test SP35xx Audio Test 169 122 (72,28) a. T157-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 148 71 (48) a. T157-124500 - Bgan-X BDU Mainboard SP35xx Audio Test 169 122 (72,28) a. T157-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 169 122 (72,28) a. T157-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 164 71 (48,08) a. T157-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 164 71 (48,08) a. T157-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 164 <td>Q</td> <td>Module Test</td> <td>SP35xx Module Test</td> <td>248</td> <td>140 (56,5%)</td> <td>ଭ</td> <td>ТТ59-123533 - gammel Инструменты СІМ Производство</td> <td>SP35xx Module Test</td> <td>216</td> <td>95 (44,0%</td>	Q	Module Test	SP35xx Module Test	248	140 (56,5%)	ଭ	ТТ59-123533 - gammel Инструменты СІМ Производство	SP35xx Module Test	216	95 (44,0%
Test Iest Iest Iest 201 12 (5) TT59-123533 - gammel /H-try/MeHtal CIM Производство SP35xx Module Test 216 95 (44, 08) 4 403504A - Atex Battery Secundary 403504A Final Test 209 112 (53, 68) 4 TT60-1235XX - SP3500 Display Test SP35xx Module Test 209 112 (53, 68) 4 TT60-1235XX - SP3500 Display Test SP35xx ATEX Transceiver 171 131 (76, 68) 4 TT52-124501 - BGAN-X Generic Mainboard SP35xx Audio Test 169 122 (72, 28) 5 TT57-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 168 71 (48, 08) 4 406202 - Sailor 6202 Handmicro Sailor 6202 114 79 (61) 6 T0125807 - Protection module for D125807 - Protection module for TT60-125807 Secondary 131 (19 (90, 88)	অ অ	VHF Battery Vacuum test - Vacuum	SP35xx Battery Vacuum	245	106 (43,3%)	Q	TT57-124510 - Bgan-X BDU Mainboard	BGAN X Generic Mainboard Function Test	148	71 (48,04
a) 1759-12353 - gammel PHCTpyMeHtal SP35xx Module Test 216 95 (44, 0%) c) CIM Tpovesogcree 403504A - Atex Battery Secundary 403504A Final Test 209 112 (53, 6%) c) T160-1235XX - SP3500 Display Test SP35xx Display Test SP35xx Display Test 174 145 (83, 3%) c) Atex Tranceiver Vacuum test - SP35xx ATEX Transceiver 171 131 (76, 6%) c) Atex Tranceiver Vacuum test - SP35xx Audio Test 169 122 (72, 2%) c) T15672A - Thrane IP Handset, Wired Maritime VoIP Handset 161 135 (83, 9%) c) T157-124510 - Bgan-X BDU Mainboard BGAN X Generic 148 71 (48, 0%) c) T157-124510 - Bgan-X BDU Mainboard BGAN X Generic 148 71 (48, 0%) c) C152507 - Protection module for T160-125807 Secondary 131 119 (90, 9%) c) A06202 - Sailor 6202 Handmicro Sailor 6202 149 71 (48, 0%) c) T157-1245794 GaN X ACDC SUPPLY DC PSM 114 79 (64		test	lest			Q	403504A - Atex Battery Secundary	403504A Final Test	209	112 (53,64
Q. 403504A - Atex Battery Secundary 403504A - Final Test 209 112 (52,64) Q. TTG0-1235XX - SP3500 Display Test SP35xx Display Test 174 145 (83,34) Q. Atex Trancelver Vacuum test - Vacuum Test SP35xx ATEX Transceiver Vacuum Test 171 131 (76,64) Q. TTG2-35XX[623520 ASP3520 VHF, GMDSS] - SP3500 Audio Test SP35xx Audio Test 169 122 (72,24) Q. TTG7-124510 - Bgan-X BDU Mainboard Maritime VolP Handset Test 161 135 (83,94) Q. TTG7-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 144 71 (48, 04) Q. 06202 - Sailor 6202 Handmicro Sailor 6202 114 79 (64) Q. 06202 - Sailor 6202 Handmicro Sailor 6202 Wacuum Test 116 75 (64) Q. 0757-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 144 71 (48, 08) (47, 08) Q. 06202 - Sailor 6202 Handmicro Sailor 6202 139 123 (88, 58) (71, 48, 08) (71, 48, 08) (71, 48, 08) (71, 48, 08) (71, 48, 08) <td>୍</td> <td>СІМ Производство</td> <td>SP35xx Module Test</td> <td>216</td> <td>95 (44,0%)</td> <td>ଭ</td> <td>TT59-1235XX[SP3510/20] - SP35xx Module Test</td> <td>SP35xx Module Test</td> <td>248</td> <td>140 (56,54</td>	୍	СІМ Производство	SP35xx Module Test	216	95 (44,0%)	ଭ	TT59-1235XX[SP3510/20] - SP35xx Module Test	SP35xx Module Test	248	140 (56,54
Q. TTG-1235XX - SP3500 Display Test SP35xx Display Test 174 145 (83, 38) Q. Atex Tranceiver Vacuum test - Vacuum Test SP35xx ATEX Transceiver 171 131 (76, 68) Q. TTG2-35XX[623520A SP3520 VHF, GMDSS] - SP3500 Audio Test SP35xx AtEX Transceiver 171 131 (76, 68) Q. TTG2-35XX[623520A SP3520 VHF, GMDSS] - SP3500 Audio Test SP35xx Audio Test 169 122 (72, 28) Q. TT-3672A - Thrane IP Handset, Wired Maritime VoIP Handset 161 135 (83, 98) Q. TT57-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 148 71 (48, 08) Q. 406202 - Sailor 6202 Handmicro Sailor 6202 199 123 (88, 58) Q. 406202 - Sailor 6202 Handmicro Sp35xx Audio Test 169 122 (72, 28) Q. TT57-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 148 71 (48, 08) Q. 406202 - Sailor 6202 Handmicro Sailor 6202 199 123 (88, 58) Q. 406202 - Sailor 6202 Handmicro Sailor 6202 199 121 (90, 88) Q. 406202 - Sailor 6202 Handmicro Sailor 6202 169	୍	403504A - Atex Battery Secundary	403504A Final Test	209	112 (53,6%)	Q	62-130933 - VHE6000 Adv Main unit	VHE6000 Adv Main Unit	107	68 (63,64
vacuum rest	ର ର୍	TT60-1235XX - SP3500 Display Test Atex Tranceiver Vacuum test - Vacuum test	SP35xx Display Test SP35xx ATEX Transceiver	174	145 (83,3%) 131 (76,6%)	୍	TT57-124671 - BGAN-X HPA	BGAN-X Generic HPA Test	121	78 (64,5
a. TT-3672A - Thrane IP Handset, Wired Maritime VoIP Handset 161 135 (83, 9%) b. TT-3672A - Thrane IP Handset, Wired Maritime VoIP Handset 161 135 (83, 9%) b. TT57-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 148 71 (48, 0%) b. 406202 - Sallor 6202 Handmicro Sallor 6202 139 123 (88, 5%) b. DC-25807 - Protection module for Paseud AFEY TT60-125807 Secondary ATEY Battery 131 119 (90, 8%)	ର୍	TT62-35XX[623520A SP3520 VHF, GMDSS1 - SP3500 Audio Test	SP35xx Audio Test	169	122 (72,2%)	Q	406202 - Sailor 6202 Handmicro	Sailor 6202 Vacuum Test	116	75 (64,7
B TT57-124510 - Bgan-X BDU Mainboard BGAN X Generic Mainboard Function Test 148 71 (48, 0%) Q Offschulz Salior 6202	ର୍	TT-3672A - Thrane IP Handset, Wired	Maritime VoIP Handset Test	161	135 (83,9%)	ଷ୍	57-127957[BGANX ACDC SUPPLY 406080A] - BGAN X ACDC SMPS	DC PSM	114	79 (69,3
4 406202 - Sailor 6202 Handmicro Sailor 6202 139 123 (88,5%) 60-125807 - Protection module for Pasced AFEY TT60-125807 Secondary ATEX Pattery 131 119 (90,8%)	হ	TT57-124510 - Bgan-X BDU Mainboard	BGAN X Generic Mainboard Function Test	148	71 (48,0%)	Q	TT62-35XX[623520A SP3520 VHF, GMDSS] - SP3500 Audio Test	SP35xx Audio Test	169	122 (72,24
60-125807 - Protection module for TT60-125807 Secondary 131 119 (90, 8%) Atex Battery Vacuum test - Vacuu	হ	406202 - Sailor 6202 Handmicro	Sailor 6202	139	123 (88,5%)	Q	TT57-124794 - Wired Thrane IP Handset Mainboard	VoIP Handset	129	94 (72,9
Vacuum Test	হ	60-125807 - Protection module for B3504, ATEX	TT60-125807 Secondary ATEX Battery	131	119 (90,8%)	Q	Atex Battery Vacuum test - Vacum test	SP35xx ATEX Battery Vacuum Test	124	94 (75,84

Dashboard information for the past 30 days created 2016-05-20 22:09:49. Items with less than 100 tests excluded.

Data is loaded when page is shown. By clicking the S button, the view is refreshed with the latest data available. The number of days and minimum number of tests to take into consideration in this view can be adjusted in the personal settings (see section 6.1).



3 Reports

To enter Report main page, click the 'Reports' text in menu line.

FACTS Dashboard Reports System Administrator

The page presents the available reports (depends on the current user rights).



To select a report, move the mouse over the appropriate report square and select.

3.1 Navigating in Data grids

When report results are presented in a grid (table) as shown below, the following navigation can be used.

Ľ D	ata										~
Q				₩ S	howing 1 to 10	of 36 entries					
	Test 🔺	Test step	Ср 🖕	Cpk 🔶	Cpk USL 👙	Cpk LSL 🔶	Mean 🔶	σ	Min USL	Max LSL 🔶	Measurements 🔶
Q	WRT54x Final Test	Adjust 1.8v Supply	1,158	0,792	0,792	1,524	1,800 E+00	4,391 E-03	1,811 E+00	1,780 E+00	2.633
Q	WRT54x Final Test	Adjust RF Clock	3,335	3,319	3,352	3,319	-29,982 E-03	599,657 E-03	6,000 E+00	-6,000 E+00	2.633
Q	WRT54x Final Test	Adjust RF TX Modulation	4,562	3 ,079	3,079	6,046	37,976 E+00	219,183 E-03	40,000 E+00	34,000 E+00	2.633
Q	WRT54x Final Test	Check 1.8v SUPA	3,345	3 2,026	2,026	6 4,665	1,909 E+00	14,946 E-03	2,000 E+00	1,700 E+00	2.633
Q	WRT54x Final Test	Check 1.8v SUPB	2,977	1,800	1,800	4,154	1,909 E+00	16,796 E-03	2,000 E+00	1,700 E+00	47
Q	WRT54x Final Test	Check 3.0v ESUPA	2,593	6 0,489	0,489	0 4,697	3,177 E+00	83,556 E-03	3,300 E+00	2,000 E+00	2.633
Q	WRT54x Final Test	Check 3.0v ESUPA.1	1,954	0,422	0,422	3,486	892,098 E-03	85,296 E-03	1,000 E+00	0	47
Q	WRT54x Final Test	Check 3.0v ESUPA.2	7,911	1,442	1,442	14,379	3,182 E+00	27,389 E-03	3,300 E+00	2,000 E+00	47
Q	WRT54x Final Test	Check Supply Current A	0,599	0,450	0,450	0,749	67,469 E-03	16,683 E-03	90,000 E-03	30,000 E-03	2.632
Q	WRT54x Final Test	Check Supply Current B	0,611	0,438	0,438	0,783	68,464 E-03	16,380 E-03	90,000 E-03	30,000 E-03	47

Text can be searched in columns containing text. In the above screenshot the Test and Test step columns can be searched. To search, simply enter a text in the search field. The text can be any part of the texts contained in the searched columns.

Example of search with "adj"



Data										~
adj			₩ S	Showing 1 to 3 o	of 3 entries (filte	red from 36 total e	ntries)			
Test 🔺	Test step	Cp	Cpk 👙	Cpk USL	Cpk LSL	Mean 🔶	$\sigma \clubsuit$	Min USL 🔶	Max LSL 🔶	Measurements 🔶
WRT54x Final Test	Adjust 1.8v Supply	1,158	0,792	0,792	1,524	1,800 E+00	4,391 E-03	1,811 E+00	1,780 E+00	2.633
WRT54x Final Test	Adjust RF Clock	3,335	3,319	3,352	3,319	-29,982 E-03	599,657 E-03	6,000 E+00	-6,000 E+00	2.633
WRT54x Final Test	Adjust RF TX Modulation	4,562	3 ,079	3,079	6,046	37,976 E+00	219,183 E-03	40,000 E+00	34,000 E+00	2.633
	Data adj Test A WRT54x Final Test WRT54x Final Test WRT54x Final Test	Data Q adj Test Test step Q WRT54x Final Test Adjust 1.8v Supply Q WRT54x Final Test Adjust RF Clock Q WRT54x Final Test Adjust RF TX Modulation	Data M P Q adj M M Test Test step Cp + Q WRT54x Final Test Adjust 1.8v Supply 1,158 Q WRT54x Final Test Adjust RF Clock 3,335 Q WRT54x Final Test Adjust RF TX Modulation 4,562	Test Test step Cp Cp (cp (cp (cp (cp (cp (cp (cp (cp (cp (c	Test Test step Cp + Cpk USL + Q WRT54x Final Test Adjust 1.8v Supply 1,158 0,792 0,792 Q WRT54x Final Test Adjust RF Clock 3,335 3,319 3,352 Q WRT54x Final Test Adjust RF TX Modulation 4,562 3,079 3,079	Test Test step Cp Cpk Cpk USL Cpk LSL Cpk Cpk USL Cpk LSL Cpk Cpk USL Cpk USL Quadratic Cpk USL Quadratic Quadratic <t< th=""><th>Data Test step Cp + Cp + Cpk USL + Cpk USL + Mean + Q Adjust 1.8v Supply 1,158 0,792 0,792 1,524 1,800 E+00 Q WRT54x Final Test Adjust RF Clock 3,335 3,319 3,352 3,319 -29,982 E-03 Q WRT54x Final Test Adjust RF TX Modulation 4,562 3,079 3,079 6,046 37,976 E+00</th><th>Data R Image: Colspan="4">Showing 1 to 3 of 3 entries (filtered from 36 total entries) Test step Cp & Cpk & Cpk USL & Cpk LSL & Mean & σ & general entries R WRT54x Final Test Adjust 1.8v Supply 1,158 0,792 0,792 1,524 1,800 E+00 4,391 E-03 8,335 3,319 3,352 3,319 -29,982 E-03 599,657 E-03 8,079 8,079 6,046 37,976 E+00 219,183 E-03 209,183 E-03 209,183</th><th>Data M < M</th> M M Showing 1 to 3 of 3 entries (filtered from 36 total entries) Test step Cp & Cpk & Cpk USL & Cpk LSL & Mean & o & Min USL & Q Adjust 1.8v Supply 1,15c 0,792 0,792 1,524 1,800 E+00 4,391 E-03 1,811 E+00 Adjust RF Clock 3,335 3,319 3,352 3,319 -29,982 E-03 599,657 E-03 6,000 E+00 40,000 E+00 Adjust RF TX Modulation 4,562 3,079 3,079 6,046 37,976 E+00 219,183 E-03 40,000 E+00</t<>	Data Test step Cp + Cp + Cpk USL + Cpk USL + Mean + Q Adjust 1.8v Supply 1,158 0,792 0,792 1,524 1,800 E+00 Q WRT54x Final Test Adjust RF Clock 3,335 3,319 3,352 3,319 -29,982 E-03 Q WRT54x Final Test Adjust RF TX Modulation 4,562 3,079 3,079 6,046 37,976 E+00	Data R Image: Colspan="4">Showing 1 to 3 of 3 entries (filtered from 36 total entries) Test step Cp & Cpk & Cpk USL & Cpk LSL & Mean & σ & general entries R WRT54x Final Test Adjust 1.8v Supply 1,158 0,792 0,792 1,524 1,800 E+00 4,391 E-03 8,335 3,319 3,352 3,319 -29,982 E-03 599,657 E-03 8,079 8,079 6,046 37,976 E+00 219,183 E-03 209,183	Data M < M	Data M < M

If a table contains more rows than defined by a user setting, the paging control is enabled. To navigate through the pages, click arrow icons or page number directly.

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Showing 1 to 25 of 1,000 entries

The sort order of the table can be set to order from high to low, or low to high. Further, the sort order can be controlled by selecting multiple columns headers (hold shift key while clicking the headers). When multi selecting, the sort order is determined by the order the columns is selected. Click a column header once to choose low to high sorting, and click twice to select high to low sorting.



3.2 Navigating in charts

In reports containing graphs, the following navigation can be used.

3.2.1 XY - chart



Meaning of circle and triangle:

Circles represent a single measurement, triangles represent a group of measurements.

Tooltip: By moving the mouse curser over either a circle or a triangle, detailed information appears.



If the mouse is clicked on a circle, the report Unit Overview is shown, with filter options filled out corresponding to the selected unit.





3.2.2 Normal distribution chart



Each bars represent a percentage of measurements. Hold the mouse over a bar to see a tooltip with detailed information:



3.2.3 Zoom

The zoom mode is controlled by the buttons "X axis", "Y axis" and "Both axes".

Zoom X axis Y axis Both axes Reset

"X axis" – Zoom in only on X axis

"Y axis" – Zoom in only on Y axis

"Both axes" – Zoom in by selection rectangle

To reset zoom level back to the initial level, press reset button, or double click the graph.

3.2.4 Scale

Some charts allow switching between linear and logarithmic scale. This functionality is controlled by the button "Linear" and "Logarithmic".



"Linear" – Linear scale on X axis "Logarithmic" – Logarithmic scale on X axis



3.3 Exporting reports

Most reports can be exported to Microsoft Excel and Adobe PDF.

3.3.1 Export to PDF

This report type exports all the result data including graphs, filter settings etc.

To export to PDF, select menu item "Export" and then Report to PDF. The report is generated on the server and presented as a download file.

3.3.2 Export to Excel

This report type exports all the result data for the report. Filter selection is presented on the first page, and the data on second page.

To export to Excel, select menu item "Export" and then Report to Excel. The report is generated on the server and presented as a download file.

3.4 Filtering reports

All reports are made based on test data selected with filter. Each report has a set of default filter options and some additional advanced filter options:



By clicking the Default button, all default filtering options are visible. Clicking the Advanced button makes further filter options available for the selected report.

Whenever possible, the selected filtering options are transferred when switching between different types of reports.

Clicking the Reset button causes all filtering options to be reset to their initial state and value.



3.5 SPC report

Statistical analysis result for test steps represented by mean value, standard deviation (σ), C_p and C_{pk} index values as well as specification limits. For further information on the calculated statistical values, please refer to section 7.

Typical use:

The SPC report contains the results of the statistical analysis performed on the data selected by the filter criteria. Please notice, that the correct use of the SPC report presumes the filtered data is normal distributed and lies within the normal distribution "Bell Curve" (see further explanation in section 3.6).



The capability values C_p and C_{pk} are used to indicate the performance of the production processes involved in generating the selected data. Typically these values are used in Six Sigma process optimizations to give a direct indication of a process' sigma level and the defects PPM (Defect Parts Per Million) See estimated conversion table below:

C _{pk} value	Sigma level	Defects (PPM)
0.333	1	691000
0.667	2	308500
1.000	3	66800
1.333	4	6200
1.667	5	230
2.000	6	3.4

Please note, at the above show conversion between sigma level and C_{pk} value is an estimate. Further, the conversion assumes a 1.5 sigma shift. For further details please refer to Six Sigma literature.

Notes on specification limits (Min USL and Max LSL):

In some cases, the upper and lower specification limits (USL and LSL) vary within the data selected by the filter. In those cases, all statistical values are calculated from a worst case perspective, using the minimum upper specification limit and the maximum lower specification limit found in the filtered data. When presented in the SPC report, these values are denoted Min USL and Max LSL, respectively. All calculated



statistical values in the SPC report are calculated using the formulas described in section 7, using the Min USL and Max LSL as specification limits in the formulas.

Notes on Cp and Cpk values:

By definition, the C_{pk} value is the adjustment of C_p for the effect of non-centered distribution (a centered distribution has its mean value right in the middle of LSL and USL). C_{pk} is calculated both against USL (denoted C_{pk} USL) and against LSL (denoted C_{pk} LSL). The final C_{pk} value is the lower of these two values. This means, that if the distribution is centered or close to centered, C_{pk} equals C_p . On the other hand, if C_{pk} is relatively much less than the C_p value, this indicates a mean value far off the center of USL and LSL. In these cases, something significant might have changed within the production process, or perhaps USL or LSL simply needs adjustment to cope with changed circumstances. C_{pk} values above 2, corresponding to less than 3.4 defects per million is a clear indication that USL and LSL are set at a level allowing almost everything to pass through the test.

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orts / SPC											
Filter											
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Items	CIM-100 ×								Тур	e name to sa	ve a filter templa
Test	*						•			🗸 Save	💼 Delete
Test step	*						-				
Test result	Passed	-]								
Test run	Last test run	-									
Test step result	Passed	•]								
Test step cycle	Last test step cycle	-]								
	Q Search		_								
Data											
2	M 4	► ► Showing	1 to 2 of 2 e	entries							
Test		▲ Test step	Ср 🕴	Cpk 🔶	Cpk USL ∲	Cpk LSL ≑	Mean 🔶	σ 🔶	Min USL 🔶	Max LSL ≑	Measurements
Computer Metherheard	Fest Sequence Loop	MainSequence:Keyboard Test					6,002 E+00	5,686 E- 03		5,000 E+00	2
(MainSequence)											

To get the SPC report, fill out the appropriate filter options and click the Search button.

To see measurements in a "Time Series report", simply click the magnifying glass in the first column of each row. This opens the Time Series report with prefilled filter options according to the selected test step.



3.6 Time Series report

Time based XY-graph and the normal distribution graph of the measurements for a specific test step. Statistical analysis values are shown for the selected measurements.

Typical use:

Based on the filter criteria including a specific test step, the Time Series report shows three pieces of information:

- Calculated Values: All calculated statistical values for the given filter criteria. These values correspond to the values visible on the SPC report. Also visible are additional values corresponding to the mean value minus/plus 3 times standard deviation. These values are denoted -3σ and +3σ and are normally called "control limits".
- Series Chart: Time based XY chart showing all measurements for the given filter criteria. The chart also contains indications of the values USL, LSL as well as the above mentioned control limits, denoted -3σ and $+3\sigma$.
- Distribution Chart: Chart showing the distribution (population) of the measurements in the given filter criteria. Following the prerequisite that SPC can only be done on data, which has a normal distribution, the chart should show a clear "Bell Curve" of the distribution. The chart also contains indications of the values Min USL, Max LSL as well as the above mentioned control limits, denoted -3σ and +3σ.

The Time Series report can be used to check the normal distribution of the selected data. According to the empirical rule for normal distribution, only 0.3% of the measurements should lie outside the control limits. This means, that in case the distribution shows more than 0.3% outside the control limits, the distribution might not have a proper normal distribution, or the process producing the measurements are out of statistical control. Production outside statistical control is a good reason to check the selected data further.



To get the Time Series report, fill out the appropriate filter options and click the Search button.

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Calculated Values		•
Cp Cpk	Cpk USL Cpk LSL Mean σ +3 σ -3 σ Min USL Max LSL	Measurements
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Series Chart		~
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3.7 Test Result report

The report shows the most recent test data and test results imported by the system.

Typical use:

The Test Result report is typically used to get an overview of what has recently been tested in the production. It provides an overall overview of tests performed on units, the number of re-tests performed, test station names and test operators.

By setting the appropriate filter options, the report can be used to see what has been tested on a given station. It also provides an efficient tool to check if re-testing is widely used for certain products or certain periods during the day. By entering a specific serial number for a unit in the filter options, test data for that specific unit can be found and displayed.

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Test Result								
r								
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6-05-16 21:31:17	SN635990310772683750	CIM-100	Computer Motherboard Test Sequence Loop (MainSequence)	Passed	1 of 1	OS-TEST	administrator	2016-05-16 21:31:30
6-05-09 13:33:31	SN635983976119089766	CIM-100	Computer Motherboard Test Sequence Loop (MainSequence)	Passed	1 of 1	OS-TEST	administrator	2016-05-09 13:33:38
6-05-05 22:05:05	SN635980827059358281	CIM-100	Computer Motherboard Test Sequence Loop (MainSequence)	Passed	1 of 1	OS-TEST	administrator	2016-05-05 22:05:12
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16-05-05 22:05:05 16-05-05 02:17:07 16-05-03 03:28:16 16-04-26 03:16:41 16-04-26 03:51:02 16-04-08 15:21:06 16-04-06 05:03:42 16-04-06 00:30:24 16-04-05 21:14:54 16-03-29 01:19:06	SNN3590802790538281 SNN3590114273202031 SN635978428957463750 SNN5597237414101250 SNN5597153062657500 SNN55957556695153750 SNN55955497427019250 SNN55954876427019250 SNN5595487642776	CIM-100 CIM-100 CIM-100 CIM-100 CIM-100 CIM-100 CIM-100 CIM-100 CIM-100	Computer Motherboart Test Sequence Loop (MainSequence) Computer Motherboart Test Sequence Loop (MainSequence) Computer Motherboard Test Sequence Loop (MainSequence) Computer Motherboart Test Sequence Loop (MainSequence)	Pased Pased Pased Pased Pased Pased Pased Pased Pased	1 of 1 1 of 1	05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST	administrator administrator administrator administrator administrator administrator administrator administrator administrator administrator	2016-05-05 22 05:12 2016-05-05 02:17 09 2016-05-03 03:28 22 2016-04-26 03:16 45 2016-04-26 03:51:29 2016-04-26 05:51:29 2016-04-06 05:05:52 2016-04-06 00:30:33 2016-04-06 00:30:33 2016-04-05 01:16:31
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166/65/22/26/66 166/65/22/26/66 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/65/20/28 166/28/20/28 16/28/28 16/28/28 16/28/28 16/28/28 16/28/28 16/28/28 16/2	SNN3598082790334281 SNN55980114279202031 SNN55972374014279202031 SNN5597237401401250 SNN5597237401401250 SNN55957256600153750 SNN55956158221091250 SNN5595487248903760 SNN5595487248903760 SNN5595487248903760 SNN55954876480555038500 SNN559512577203155000 SNN559512577203155000 SNN559512577203155000 SNN559512577203155000 SNN55951257720315200	CIM-100 CIM-10	Computer Motherboart Test Sequence Loop (MainSequence) Computer Motherboart Test Sequence Loop (MainSequence)	Passed Passed	1 of 1 1 of 1	05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST 05-TEST	administrator administrator	2016-05-05 22:05:12 2016-05-05 02:17:09 2016-05-03 02:822 2016-04-28:03:162 2016-04-28:03:162 2016-04-26:05:123 2016-04-06:05:05:22 2016-04-06:05:32 2016-04-06:07:14:55 2016-04-05:21:14:55 2016-04-05:21:14:55 2016-04-05:21:14:55 2016-04-05:22:56:41 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:23:25:54 2016-02:20:40:37 2016-02:23:25:54 2016-02:20:40:37 2016-02:40:40:40:40:40:40:40:40:40:40:40:40:40:
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To get the Test Result report, fill out the appropriate filter options and click the Search button.



3.8 Unit Overview report

Test step result and measurements for all performed test runs for a specific item serial number.

Typical use:

The Unit Overview report is typically used to get full test reports for specific units. The report includes a list of all related units. The relation of units is setup in the import of data. Via the Unit Relations table, it is possible to navigate to any of the related units.

In case a unit has been tested more than once, the performed tests can be selected and shown side-byside. This way it is easy to get an overview and compare the results of each test step and any differences in test conditions and parameters.

The report can also be used as an easy way to get full product test documentation in case the product undergoes repair or the like.

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To get the Unit Overview report, fill out the filter options and click the Search button.



To see and compare specific test step measurements, select appropriate tests in the "Test Overview" section. The view is automatically updated during test selection.

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3.9 Test Yield report

Numeric details and bar-graph of the yield for a number of selected tests. Each bar in the graph shows the passed/failed relation of the performed tests.

Typical use:

The Test Yield report is typically used get an overview of the actual yield and percentage yield for tests performed on a given product or product group. Normally all attention should be focused on maximizing first-pass yield, as any subsequent tests will add cost to the product and hence lower production efficiency. So, comparing first-pass yield with last-pass yield gives a tangible indication of production inefficiency and added costs. Of course, when looking at yield, the production volume is also a key element to determine where to focus any production optimizing efforts in order to get the best payback.

Another way to use this report is to compare the yield results of different time periods and thereby directly compare the production capability for time periods or different shifts, operators etc.



To get the Test Yield report, fill out the appropriate filter options and click the Search button.

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A tooltip with detailed information will appear when holding the mouse pointer on bars in the graph.

Remark

Selecting an item, leaving the filter option "Tests" at the default value (*) "All tests", will not give the net production yield for the selected item. In order to get the net production yield, the last test performed before shipping must be selected as a filter option along with the Item itself.



3.10 Test Step Yield report

Numeric details and graphical presentation of the yield for each individual test step for a selected test. The combined bar-graph shows test steps and their yield.

Typical use:

The Test Step Yield report can be used to determine which of the performed tests are the most likely to fail, and which steps are most likely to always succeed. A common picture on this report indicates that half of the test steps performed hardly ever fails. There can be several reasons behind this, but it could be a sign, that the specification limits (USL and LSL) for these test steps are too conservative, and as a result almost never catches any errors. Another reason could be that the step is not necessary at all. Whatever the reason, a test step that does not directly improve quality by catching errors, could be considered a waste of testing time and an undesired increase in production time and costs. Put together it might be a potential for increased yield.



To get the Test Step Yield report, fill out the appropriate filter options and click the Search button.

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A tooltip with detailed information will appear when holding the mouse pointer on bars in the graph.



3.11 Test Step Error Pareto report

Sorted list of most frequent failed test steps for a selected item.

Typical use:

The Test Step Error Pareto report is very similar to the Test Step Yield report and essentially shows the same data. The only difference is that it focuses on errors (failed tests), where the Test Step Yield report focuses on succeeded tests. The two reports can be used for the same purposes. Please refer to section 3.10 for further description on the use of these reports.

To get the Test Step Error Pareto report, fill out the appropriate filter options and click the Search button.

ACTS Dashboard	Reports	System						Export +	Administrato
eports / Test Step Error Pare	to								
▼ Filter									~
Test period	2016-04-22	- Today 00:0	0:00 - 23:59:59 Range Window				Default	Advanc	ed Reset
Item groups	*						(New fil	ter template)	•
Items	CIM-100 ×						Type na	me to save a	a filter template
Tests	*						✓ \$	Save	🛍 Delete
Test run	Last test run	1	•						
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	Q Search								
bata									~
Q		₩ ◀ ► ►	Showing 1 to 4 of 4 test steps						
Test			♦ Test step	♦ Total ♦	Passed	Failed	Aborted	Error 👙	Failure % 🔻
Computer Motherboard Test	Sequence Loop	(MainSequence)	MainSequence:Video Diagnostics	1	0	1	0	0	100,0
Computer Motherboard Test	Sequence Loop	(MainSequence)	MainSequence:Keyboard Diagnostics	1	0	1	0	0	100,0
Computer Motherboard Test	Sequence Loop	(MainSequence)	MainSequence:Video Test	8	7	1	0	0	12,5



3.12 Test Duration report

Time based stacked bar-graph showing the relation between the total test and handling time for selected tests. The number of tests performed is shown in a separate XY-line.

Typical use:

The Test Duration report can be used to map the time used to test a product. It shows the relation between testing time and handling time between two tests. Handling time is defined as the time from the end of one test until the beginning of the next test. In essence, handling time is waste and hence loss of production efficiency, so all efforts should be made to minimize handling time (provided there is a significant production volume to pay for the investment). Poor handling time can originate from a number of different sources – naming a few:

- Test fixtures and connectors are too difficult and time consuming to handle
- Products undergo transport between tests
- Manual handling is too slow

Whatever the reason is for the poor handling time, it should be properly investigated, perhaps as part of a LEAN project to optimize production logistics and maybe even reduce or simplify production steps. Like the Test Yield report, the Test Duration report can also be used to compare performance as a function of time periods, operators, test fixtures or shifts.



To get the Test Duration report, fill out the appropriate filter options and click the Search button.

FACTS Dashboard	d Reports System	Export - Administrator -
Reports / Test Duration		Θ
▼ Filter		*
Test period	2016-04-22 - Today 00:00:00 - 23:59:59 Range Window	Default Advanced Reset
Item groups	•	(New filter template)
Items	CIM-100 ×	Type name to save a filter template
Tests	•	✓ Save 🛍 Delete
Test result	Passed •	
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A tooltip with detailed information will appear when holding the mouse pointer on bars in the graph.



3.13 Test Step Duration report

Detailed duration information for all test steps in a test.

Typical use:

The Test Step Duration report can be used to get a deeper insight into time it takes for each test step to complete. The report provides simple statistics for the time spent for each test step, including average duration, standard deviation and worst duration. As test time is one of the limiting elements for production capacity, efforts should be made to investigate and optimize any test step taking up to majority of time.

When looking at time spent on test steps, it is also very interesting, if any of the "unnecessary test steps" found via the Test Step Yield report is also taking up lots of time when testing. In that case, much time is spent on completing test steps that hardly ever fail – perhaps a serious candidate for optimization.

To get the Test Step Duration report, fill out the appropriate filter options and click the Search button.

	d Reports	System				Export 🗸	
oorts / Test Step Duration							
Filter							
Test period	2016-04-22 -	Today	00:00:00 - 23:59:59 Range Window			Default Advanced	Reset
Item groups	*					(New filter template)	-
Items	CIM-100 ×					Type name to save a filte	er template
Tests	*					✔ Save í	Delete
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Test step cycle	Last test step	cycle	-				
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Data Q		₩ ◄ ►	Showing 1 to 20 of 20 test steps				
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3.14 XY Graph report

Numeric array based XY-graph and min/max XY-graph for a set of specified test steps and channels.



- XY chart: Shows the numeric measurements for selected channels.
- Min/max chart: shows the average, min and max values for the selected channels.

ACTS Dashboa	d Reports System		Export -	Administrator
oorts / XY Graph				
⁷ Filter				~
Test period	2016-04-22 - Today 00:00:00 - 23:59:5	Range Window	Default Advanced	Reset
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Show 🕴 Test time	y Serial no.	Test step	🕴 Test step result ≬	Test run 💧
2016-04-30 00:0	0:00 Afd705de9-f9d8-4390-bdf9-e1f3e0679d82	TestStepResult#30-Apr-16 0:00:00 AM#5	#20#20#200 Passed	1 of 1
2016-04-29 00:0	0:00 Ae3e0f179-42d9-4ce4-94ce-081519fd2780	TestStepResult#29-Apr-16 0:00:00 AM#5	5#20#20#200 Passed	1 of 1
2016-04-28 00:0	0:00 A9b6a6777-cae0-4aa1-90fe-c7695e0162f8	TestStepResult#28-Apr-16 0:00:00 AM#5	#20#20#200 Passed	1 00 1
2016-04-27 14:	0:00 A99a9b700-6681-45b8-8a3c-a5ae282394h9	TestStepResult#27-Apr-16 0:00:00 AM#5	Hassed #20#20#200 Failed	1 of 1
2016-04-26 00:0	0:00 Aa353ca78-cf52-48d7-b2c0-9b5a26fa2f65	TestStepResult#26-Apr-16 0:00:00 AM#5	#20#20#200 Passed	1 of 1
2016-04-25 00:0	0:00 Ab0dc6bed-8c97-414f-98d5-2a9ebeae0bcd	TestStepResult#25-Apr-16 0:00:00 AM#5	#20#20#200 Failed	1 of 1
2016-04-24 00:0	0:00 Abdee81e3-51f6-4817-9e33-758f7dcee478	TestStepResult#24-Apr-16 0:00:00 AM#5	#20#20#200 Passed	1 of 1
2016-04-23 00:0	0:00 A1ca23e24-fcf7-43c3-a09e-1fc25907514f	TestStepResult#23-Apr-16 0:00:00 AM#5	#20#20#200 Failed	1 of 1
2016-04-22 00:0	0:00 Ac/eb39ca-6127-405c-b1ec-10fff2f6c5fe	TestStepResult#22-Apr-16 0:00:00 AM#6	#20#20#200 Passed	1 01 1
	10023442343	Default relay output values	Channel2	
	10023442343	Default relay output values	Channel2	
2	10023442343	Default relay output values	Channel3	
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Min/Max Chart Zoom X axis Y axis 4 2 0 8 6 6 4 2	Both axes Reset Scale Linear Logarit		Macimum Average Minimum	
.0 /				



Both the XY chart and the Min/Max chart allows switching between logarithmic and linear scale. This is done using the buttons, located next to the zoom functionality.



Both charts default to linear scale.

3.15 Audio Graph report

Audio based XY-graph for a specific test step.

Typical use:

Based on the filter criteria including a specific test step, the Audio Chart shows the actual measurements and potential upper- and lower- limits.

- Audio Chart: Shows measurements for the selected test steps and potential limits.
- **Min/Max chart:** Shows the average, higher and lower measurements of all the combined test steps.



<pre>rtai to the state of the state of</pre>	Clearance Advanced Resetting (New filter template) • Type name to save a filter template • ** Blave • • 3 c 6 3 1,18801 • 3 c 6 3 1,18801 • 3 c 6 3 1,18801 • 3 c 6 3 1,28001 • 3 c 6 3 4,6503 1,4,6703 3 c 7 3 942,16036 • 3 c 6 3 9424,4036 • 3 c 7 3 9494,4039 • 3 c 7 3 9494,4036 • 2 c 7 2 5,2804 • 2 c 7 2 5,2804 • 2 c 7 2 9,28437 • 2 c 7 2 9,28437 • 2 c 7 2 9423,4031 •
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	Image: Clearance Sensitivity 3 of 3 1,3801 3 of 3 2,0004 3 of 3 9424,0005 2 of 2 1,2300 2 of 2 1,2320 2 of 2 1,2327 2 of 2 1,2327 2 of 2 1,2327 2 of 2 1,2327
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a) 12:10:11 00378213911 Receive Electical. LEO Jack Leophack Sitter B Persone Passed 2 of 2 19:21,210:11 a) 20:20:01:12:10:14 00378213911 Receive Electical. LEO Jack Leophack Left B Response Passed 2 of 2 19:21,200:11 a) 20:20:01:12:10:14 00378213910 Receive Electical. LEO Jack Leophack Left B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:10:21 00378213100 Receive Electical. LEO Jack Leophack Left B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:10:21 00378213100 Receive Electical. LEO Jack Leophack Studt B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:10:21 00378213100 Receive Electical. LEO Jack Leophack Studt B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:12:10 00378213100 Receive Electical. LEO Jack Leophack Studt B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:12:10 00378213100 Receive Electical. LEO Jack Leophack Studt B Response Passed 2 of 2 19:23,200:11 a) 20:20:01:12:12:10 0037821300 Receive Electical. LEO Jack Leophack Studt B Response Passed 2 of 2 0,21:23:23 a) 20:20:20:12:12:12:11	2 c ≤ 2 4953,2201 -71,43 2 c ≤ 2 4942,7702 28,43 2 c ≤ 2 4942,4007 28,43 2 c ≤ 2 1,43547 -80,43 2 c ≤ 2 1,43547 -80,43 2 c ≤ 2 1,4354 2,67 2 c ≤ 2 1,4354 2,67
a) 12:06:11 12:16:10 00278213911 Receive Electrical. LEO Jack Loophack High E Response Passed 2 a c 2 1 4:42,12021 a) 21:06:11 12:16:21 002378213100 Taraxenk. LEO TX Response F Response Passed 2 a c 2 1 4:42,12021 a) 21:06:11 12:16:21 002378213100 Taraxenk. LEO TX Response F Response Passed 2 a c 2 1 4:4324 a) 21:06:11 12:16:21 002378213100 Reachack LEO Txedhack I Response Passed 2 a c 2 4 4:4324 a) 21:06:11 12:16:21 002378213100 Reachack LEO Txedhack I Response Passed 2 a c 2 4 4:4324 a) 21:06:11 12:16:21 002378213100 Reachack LEO Taekach Short B Response Passed 2 a c 2 4 4:4324 a) 21:06:11 12:16:21 002378213100 Reachack Leophack Short B Response Passed 2 a c 2 4 9:432,49:029 a) 21:06:11 12:16:21 002378213100 Reachack Leophack Leophack Short B Response Passed 2 a c 2 4 9:432,49:029 a) 21:06:11 12:16:21 002378213100 Reachack Leophack Leophack Leophace Short B Response Passed 2 a c 2 4 9:432,49:029 a) 21:06:11 12:16:21 002378213105 Reachack Leophack Leophack Leophace Leophace Right B Respon	
a) 202.00-31 12 10-14 00237021391H Receive Electrical. LEO Jack Leophonk Left B Response Passed 2 of 2 9492-0431 202120-051 12 10-21 00237021300B Receive, LEO TX Response Response Passed 2 of 2 143834 202120-051 12 10-21 00237021300B Receive, LEO TX Response Response Passed 2 of 2 143834 202120-051 12 10-21 00237021300B Receive, LEO TX Response Response Passed 2 of 2 143834 202120-051 12 10-21 00237021300B Receive, ELO THO Severg K Response Passed 2 of 2 143834 202120-051 12 10-21 00237021300B Receive Electrical. LEO Jack Leophock High Response Passed 2 of 2 44392,4003 202120-051 12 10-21 00237021300B Receive Electrical. LEO Jack Leophock High Response Passed 2 of 2 4932,4003 202120-051 12 10-21 00237021300B Receive Electrical. LEO Jack Leophock High Response Passed 2 of 2 4932,4003 202120-051 12 12 10 0023702130E7 Response F Response Passed 2 of 2 6,2434 202120-051 12 1421 0023702130E7 Resboak LEO THO Sweep K Response Passed 2 of 2 6,2434	2 of 2 9482,28027 2.8,43 2 of 2 1.3383750.10 2 of 2 1.61816 2.75 2 of 2 5.44592 1.6,76
a) 212-06-31 12:15.21 002/372:1300 Transmit. LEO TX Response F Response Passed 2 of 2 1.1830 a) 212-06-31 12:15.21 002/372:1300 Rescive. LEO TResponse Passed 2 of 2 1.4836 a) 212-06-31 12:15.21 002/372:1300 Rescive. LEO Tresponse Passed 2 of 2 1.4836 a) 212-06-31 12:15.21 002/372:1300 Rescive. LEO Tresponse Passed 2 of 2 1.4836 a) 212-06-31 12:15.21 002/372:1300 Rescive. Electrical. LEO Jack Loopback Sthot B Response Passed 2 of 2 1.9836 a) 212-06-31 12:15.21 002/372:1300 Rescive. Electrical. LEO Jack Loopback Lift B Response Passed 2 of 2 1.9836,003 a) 212-06-31 12:15.21 002/372:1300 Rescive. Electrical. LEO Jack Loopback Lift B Response Passed 2 of 2 1.9836,003 a) 212-06-31 12:16.21 002/372:1300 Rescive. Electrical. LEO Jack Loopback Lift B Response Passed 2 of 2 1.9836,103 a) 212-06-31 12:16.21 002/372:1300 Rescive. Electrical. LEO Jack Loopback Lift B Response Passed 2 of 2 1.9846,103 a) 212-06-31 12:16.21 002/372:1300 Rescive. Elor Y Response Passed 2 of	2 of 2 1,38367 -50,10 2 of 2 1,63656 2,75 2 of 2 5,44592 16,78
a) 212-06-31 12:15-21 0023702:1300 Receive. Lea PX. Response Response Passed 2 of 2 1.48.44 a) 212-06-31 12:15-21 0023702:1300 Rx. THO and Nake. LEO THO Sweep K. Response Passed 2 of 2 4.14.439 a) 212-06-31 12:15-21 0023702:1300 Rx. THO and Nake. LEO THO Sweep K. Response Passed 2 of 2 4.14.439 a) 212-06-31 12:15-21 0023702:1300 Receive. Electrical. LEO Jack Loophack Right B. Response Passed 2 of 2 4.43.2403 a) 212-06-31 12:15-21 0023702:1300 Receive. Electrical. LEO Jack Loophack Right B. Response Passed 2 of 2 4.03.2403 a) 212-06-31 12:16-21 0023702:1300 Receive. Electrical. LEO Jack Loophack Right B. Response Passed 2 of 2 4.03.2403 a) 212-06-31 12:16-21 0023702:1300 Receive. Electrical. LEO THO Response Passed 2 of 2 0.74877 a) 212-06-31 12:16-21 0023702:13007 Response F. Response Passed 2 of 2 0.74877 a) 212-06-31 12:16-21 0023702:13007 Receive. Electrical. LEO THO Sweep K. Response Passed 2 of 2 0.2424 a) 212-06-31 12:16-21 0023702:13007 Receive. Electrical. LEO THO Sweep K. Respon	2 of 2 1,81816 2,75 2 of 2 5,44592 16,78
a) 2012-06-31 12:16-21 (0):2372:1300 P redback. LBO Feedback. I Response Pasaed Pasaed 2 of 2 (1):4349 P.	2 of 2 5,44592 16,78
a) 212-06-31 12:152 00237021308 Results LEO THO Sweep K Response 2 012-06-31 12:152 00237021308 Results LEO THO Sweep K Response Passed 2 0 1 <td></td>	
a 12:0-0-31 12:15-1 0023702:1300 Receive Electrical. LEO Jack Loopback Sthort B Response Passed 2 of z 9922,0931 a 2012-00-31 12:16-21 0023702:1300 Receive Electrical. LEO Jack Loopback Light B Response Passed 2 of z 9932,0931 a 2012-00-31 12:16-21 0023702:1300 Receive Electrical. LEO Jack Loopback Light B Response Passed 2 of z 9932,0931 a 2012-00-31 12:16-21 0023702:1300 Receive Electrical. LEO Jack Loopback Light B Response Passed 2 of z 9932,0931 a 2012-00-31 12:16-21 0023702:13057 Receive. LEO TX Response F Response Passed 2 of z 1,6433 a 2012-00-31 12:16-21 0023702:13057 Receive. LEO TX Response F Response Passed 2 of z 3,22240 a 2012-00-31 12:16-21 0023702:13057 Receive. LEO THD Sweep K Response Passed 2 of z 3,22240 a 2012-00-31 12:16-21 0023702:13057 Receive. LEO THD Sweep K Response Passed 2 of z 3,22240 a 2012-00-31 12:16-21 0023702:13057 Receive. LEO THD Sweep K Response Passed 2 of z 3,22240 a 2012-00-31 12:16-21 Vaster All Teothexeclee Passed 2 o	2 of 2 4,11969
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a) 212-06-31 12:12-1 0023702:1300* Receive Electrical. LEO Jack Loophook. Left B Response Passed 2 of z 9:89.3984 a) 212-06-31 12:12-12 0023702:13057 Receive. LEO TX Response F Response Passed 2 of z 1.6943 a) 212-06-31 12:14-21 0023702:13057 Receive. LEO TX Response F Response Passed 2 of z 1.6943 a) 212-06-31 12:14-21 0023702:13057 Receive. LEO THO Boveponse Passed 2 of z 3.52234 a) 212-06-31 12:14-21 0023702:13057 Receive. LEO THO Sweep K Response Passed 2 of z 3.52234 a) 212-06-31 12:14-21 0023702:13057 Re THO and Neise, LEO THO Sweep K Response Passed 2 of z 3.52234 a) 210-06-31 12:14-21 0023702:13057 Re THO and Neise, LEO THO Sweep K Response Passed 2 of z 3.52234 a) 12:14-21 0023702:13057 Re THO and Neise, LEO THO Sweep K Response Passed 2 of z 3.52234 a) 12:14-21 0023702:14057 Re THO and Neise, LEO THO Sweep K Response Passed 2 of z 3.52234 Colspan="4">Colspan="4">Colspan="4">Colspan="4">Colspan="4">Colspan="4">Colspan="4">Colspan="4"Colspan="4">Colspan= 4"Colspan="4">Colspan= 4"Colspan="4"Colspan="	2 of 2 9492,40039 25,19
a) 212-06-31 12:14.21 002370213827 Transmit. LEO TX Response TResponse Passed 2 of 2 0,78877 a) 212-06-31 12:14.21 002370213827 Resolute. LEO TResponse TResponse Passed 2 of 2 0,78877 a) 212-06-31 12:14.21 002370213827 Resolute. LEO Tendback. LEO Tendback I Response Passed 2 of 2 0,28274 a) 212-06-31 12:14.21 002370213827 Resolute. LEO Tendback I Response Passed 2 of 2 0,28274 set AL Usseld:All Imart Belector Passed 2 of 2 0,22274 a) 212-06-31 12:14.21 002370213827 Resolute. LEO THO Sweep K Response Passed 2 of 2 0,22274 set AL Usseld:All Imart Belector Passed 2 of 2 0,22274 a) 212-06-31 12:14.21 002370213827 Resolute. LEO THO Sweep K Response Passed 2 of 2 0,22274 a) 212-06-31 12:14.21 Imart Belector Imart Belector Passed 2 of 2 0,22743 a) 212-06-31 12:14.21 Old and Noise, LEO THO Sweep K Response Passed 2 of 2 0,22743 c) 412-01 Imart Belector Imart Belector Imart Belector	2 of 2 9492,38965 25,220
a) 12:04-31 12:14.21 002370213827 Receive. Los PKS Response Passed 2 of z 1, 6463 a) 12:04-31 12:14.21 002370213827 Rx THD and Noise, LEO THD Sweep K Response Passed 2 of z 3, 2234 weet Als Unselect Als Investigation Passed 2 of z 3, 2234 weet Als Unselect Als Investigation Passed 2 of z 3, 2234	2 of 2 0,78877 -50,60
012-00-31 12:14:2 023702:1827 R THD and Noise, LEO THe Savees K Response Passed 2 or 2 0.2272 6.224 0.2272 012-00-31 12:14:2 023702:1827 R THD and Noise, LEO THE Savees Passed 2 or 2 0.2272 3.2274 tetcAll UnselectAll InvertBercton TetD and Noise, LEO THE Savees Save 2 or 2 0.2274 5.224 5.224 5.224 5.224 5.224 5.227 5.227 5.227 5.224 5.224 5.224 5.224 5.224 5.224 5.224 5.224 5.224 5.224 doutseld.tll tors tors tors tors tors tors	2 of 2 1,60451 3,32
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	0023782138E7 - Rx THD and Noise, LEO THD Sweep K Response (U)
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3.16 Gauge R&R

The Gauge R&R analysis (Type 2 or Type 3) can be used to quantify the amount of variation in a measure that comes from the measurement system itself rather than from product or process variations. This analysis uses the Analysis Of Variance (ANOVA) method for computing the repeatability and reproducibility.



FACTS Dashboard	Reports System					Export - Administrator
Reports / Gauge R&R						0
▼ Filter						~
Period	2013-09-29 - Today 00.00.00 - 23.59.59 Range Window					Reset
Item	10000-041	× -				Available sharing groups
Test	Gage RR	•				(New filter template)
Serial no. range	From serial no To serial no.					Type name to save a filter template
Test operator users						✓ Save 🖀 Delete
	Q. Search					
Data 🗧						*
Q	HI I I Showing 1 to 1 of 1 test results					
Test step name v	Avg Low limit Hight limit % Study VAR Total Gauge R&R	% Tolerance VAR Total Gauge R&R	% Study VAR Repeatability	% Tolerance Repeatability	% Study VAR Reproducibility	% Tolerance Reproducibility
e, test3	8592775,63 3500000 24000000 35,24	0,28	33,91		9,6	0,08
The query is limited to 10.000	st steps					

3.16.1 Details

It is possible to see details on each Gauge R&R analysis. This is done via the icon <a>!.

FACTS





3.16.2 Import

When importing Gauge R&R data it is important to tell the importer that the data is part of an GAGE R&R analysis. This is done to make sure Gauge R&R measurement data is not include in other analysis, like Yield analysis. To mark data as Gauge R&R data, then set TestCategory to 'GaugeRR' in the import files. Also make sure to include metadata on each test result, which indicates which trial it is. A test result, including trial metadata, could look like this.

```
<TestResult TestName="Gage RR" Result="Passed" TestTime="2013-12-12T12:10:18+01:00" TestCategory="GaugeRR" TestStation="OS-test2"
TestOperatorUser="TestA" TestOperatorType="GataRR">
           <Unit SerialNo="SN635346146492760001" Revision="0B28" ItemNumber="10000-042" />
           <Metadata Name="trial" Value="1" />"
                      <TestSteps>
                                  <TestStepResult Name="test2" Result="Passed">
                                             <NumericValue Comparison="GELE" UpperLimit="5.5" LowerLimit="4.1" Value="5.435" Unit="DAC" />
                                  </TestStepResult>
                       </TestSteps>
</TestResult>
<TestResult TestName="Gage RR" Result="Passed" TestTime="2013-12-12T12:11:18+01:00" TestCategory="GaugeRR" TestStation="OS-test2"
TestOperatorUser="TestA" TestOperatorType="GataRR">
           <Unit SerialNo="SN635346146492760001" Revision="0B28" ItemNumber="10000-042" />
           <Metadata Name="trial" Value="2" />"
                       <TestSteps>
                                  <TestStepResult Name="test2" Result="Passed">
                                              <NumericValue Comparison="GELE" UpperLimit="5.5" LowerLimit="4.1" Value="4.435" Unit="DAC" />
                                  </TestStepResult>
                       </TestSteps>
</TestResult>
```

4 Report filters

This chapter provides detailed information on the different report filter elements:

Hint: When showing a report based on selected filer criteria, you can copy the page link (URL) and store or send to a colleague by e-mail. When opening the copied link (URL) in an internet browser, the same report content will reappear based on the original filter options.

4.1 Filter Templates

Filter templates is an easy way to save and load any filters on a report. Filter templates are available on all report types. The list of filter templates is filtered on each report to only contain the relevant templates.



4.1.1 Using filter templates

To use a filter template to generate a report, simply open the wanted report type, then select the wanted filter in the list. The report filters will now be populated using the filter.



4.1.2 Adding filter templates

It is possible to added new filter templates before and after searching using the form.

When you have filled out the filters on form, type in a new name and click Save. Your filter will now appear in the list of filters, for the current report type and for your report widgets, so that you may add it to your dashboard.

4.1.3 Updating filter templates

To update an existing filter, simply select the filter in the list, then modify the filter options using the report filters and click Save. This will update an existing filter.

4.1.4 Deleting filter templates

To delete a filter template, select it in the list, then click Delete. You cannot delete a filter template that is being used by a widget.

4.1.5 Filter templates and Test Period

Filter templates treat Test Period selections different than reports.

Test period 2016-04-22 - Today

If Test Period contains a from-date but no to-date, filter templates will calculate how many days are between the selected date and the current and use this interval for any future reporting.

Test period 2016-04-22 - 2016-05-20

If Test period contains both dates, filter templates will save the selected dates and always use those when accessing the filter.

4.1.6 Sharing filter templates

Adding sharing groups to a filter template will allow other group-members to access the template. The shared filter template will appear in the template list, for all other members of the selected sharing groups. Note that only the creator of the template has the permission to edit or delete the template.

4.2 Filter option relations

Some filter options are inter-related. This means that for these inter-related filter options, only existing combinations can be selected as search criteria for a given report. For example: If a filter option for "Test" is filled out, all other filter options related to "Test" are pre-filtered so that they only contain values that relates to the selected value for "Test".

The following filter options are inter-related:

- Items
- Test
- Test step
- Test station
- Test fixture

4.3 Test period

Defines start and end time for data selection:





	Test period	2016-04-20]-	Today		00:00:00	-	23:59:59		Range	Window
--	-------------	------------	----	-------	--	----------	---	----------	--	-------	--------

To select a date using a calendar window, select date field with a single click. Double click a date field, if the date is entered manually using the keyboard.

Date field is formatted as [yyyy-MM-dd] (year – month – day) Time field is formatted as [hh:mm:ss] (hour – minutes – seconds)

Time span - "Range" or "Window"

Defines how data is selected over a day.

- Range: Selects all data in the time range given in Test period filter
- Window: Selects only data between start time [hh:mm:ss] and end time [hh:mm:ss] each day between start date and end date. This feature can be used to filter work shifts etc.

Example





Report time	Included in Range	Included in Window
2012-03-28 10:00:00		
2012-04-29 10:30:00	Х	
2012-04-30 00:45:00	Х	
2012-05-01 20:00:00	Х	Х
2012-06-01 23:00:01	Х	
2012-06-02 19:00:00	Х	Х

Available in the following report(s)

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Test Result	Х	
Repair Pareto	Х	
Test Yield	Х	
Test Step Yield	Х	
Test Step Error Pareto	Х	
Test Duration	Х	
Test Step Duration	Х	

4.4 Items

Limits data so that it only includes data concerning the selected items.

By default (*), all items are selected, however this is an inter-related field (see section 4.2), so a selection in one of the other related fields will influence the available contents of the Items field.

To select an item to include, set focus onto the Items field by clicking it with the mouse. A list of all available items is shown. Select an item to include by clicking it.

Items

```
1.0
10000232301 - WRT54B - Home Router
10000232302 - WRT54G - Business Router
12
12312123223 - WRT - Controller Board A
12321313223 - WRT - Controller Board B
1234
1234124
12341243
```


To select more items, simply select another item by clicking it.



To search for a specific item, simply type any part of the item number or description text.

Items	60000232301 - WRT54G - FEP * wrt
	10000232301 - <u>WRT</u> 54B - Home Router
	10000232302 - <u>WRT</u> 54G - Business Router
	12312123223 - WRT - Controller Board A
	12321313223 - WRT - Controller Board B
	33446577654 - WRT - Controller Board B with USB
	98286362712 - <u>WRT</u> 22C - Low Cost Router

Remark

If specific Test(s) are selected, the available items are limited to items related to the selected test(s). Available items can also be limited by assigned user rights.

Available in the following report(s)

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Test Result	Х	
Repair Pareto	Х	
Test Yield	Х	
Test Step Yield	Х	
Test Step Error Pareto	Х	
Test Duration	Х	
Test Step Duration	Х	

4.5 Test

Limits data so that it only includes data concerning the selected tests.

By default (*) all items are selected, however this is an inter-related field (see section 4.2), so a selection in one of the other related fields will influence the available contents of the Test field.



To select a test to include, set focus onto the Test field by clicking it with the mouse. A list of all available tests is shown. Select a test to include by clicking it.

Test

*	
	Q
BoardTest	
CPT DEMO	
CPU Mainboard	
FEP	
FlexStand OI Demo - 6TL-08	
FlexStand OI Demo - 6TL-24	
FlexStand OI Demo - 6TL-24_2	
FlexStand OI Demo - Advanced - Computer Motherboard Test Sequence	
Functional	*

To search for a specific test, simply type any part of the test name.

Test

flexst Q FlexStand OI Demo - 6TL-08 FlexStand OI Demo - 6TL-24 FlexStand OI Demo - 6TL-24_2 FlexStand OI Demo - Advanced - Computer Motherboard Test Sequence

Remark

If specific Item(s) are selected, the available tests are limited to tests related to the selected item(s). Available tests can also be limited by assigned user rights.

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Repair Pareto	Х	



4.6 Tests

Limits data so that it only includes data concerning the selected tests.

By default (*), all tests are selected.

To select a test to include, set focus onto the Test field by clicking it with the mouse. A list of all available tests is shown. Select a test to include by clicking it.

Tests		
	BoardTest	*
	CPT DEMO	I.
	CPU Mainboard	I.
	FEP	
	FlexStand OI Demo - 6TL-08	
	FlexStand OI Demo - 6TL-24	
	FlexStand OI Demo - 6TL-24_2	

To select more tests, simply select another test by clicking it.

0010		
	BoardTest	^
	CPT DEMO	
	CPU Mainboard	
	FEP	
	FlexStand OI Demo - 6TL-24_2	
	FlexStand OI Demo - Advanced - Computer Motherboard Test Sequence	
	Functional	
	Main Controllerboard	
	WRT54x Final Test	-



To search for a specific test, simply type any part of the test name.

Tests

 FlexStand OI Demo - 6TL-08 ×
 FlexStand OI Demo - 6TL-24 ×
 flexst

 FlexStand OI Demo - 6TL-24_2
 FlexStand OI Demo - Advanced - Computer Motherboard Test Sequence

Remark

If specific Item(s) are selected, the available tests are limited to tests related to the selected item(s). Available tests can also be limited by assigned user rights.

Report	Default filter	Advanced filter
Test Result	Х	
Test Yield	Х	
Test Step Yield	Х	
Test Step Error Pareto	Х	
Test Duration	Х	
Test Step Duration	Х	



4.7 Test step

Limits data so that it only includes data concerning the selected test step.

By default (*), all items are selected, however this is an inter-related field (see section 4.2), so a selection in one of the other related fields will influence the available contents of the Test Step field.

To select a test step to include, set focus onto the Test step field by clicking it with the mouse. A list of all available test steps is shown. Select a test step to include by clicking it.

Test step	*	•
		Q,
	Bit Error Rate	•
	Measure Bias Voltage	
	Packet Error Rate	
	RF Power F2	
	RF Power F2 Trimmed	
	Supply V2 Sensor	

To search for a specific test step, simply type any part of the test step name.

Test step	*	*
	bit	٩
	Bit Error Rate	

Remark

A least one item or test must be selected, before a specific test step name can be selected.

Available in the following report(s)

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Repair Pareto	Х	

4.8 Test result

Limits data so that it only includes data with the selected test result parameter.

To change the test result parameter, set focus onto the Test result field by clicking it with the mouse. A list of all available test results is shown. Select a test result to include by clicking it.



-		
0.01	rocu	11
les	resu	π.

All	
Passed	
Failed	
Aborted	
Error	

Parameters

All:	includes all test reports regardless of test result
Passed:	includes only "passed" test reports
Failed:	includes only "failed" test reports
Aborted:	includes only "aborted" test reports
Error:	includes only "error" test reports
Terminated:	includes only "terminated" test reports

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Test Result	Х	
Test Duration	Х	
Test Step Duration	Х	



4.9 Test run

Limits data so that it only includes data with the selected test run parameter. Test run is defined by the number of times an individual unit has been tested in the same test.

Test run

All test runs	
All test runs	
First test run	
Last test run	
Test run equals	· ·
Test run less than	
Test run greater than	

Parameters

All test runs	Include all test runs in selected data
First test run	Only the first test run is selected
Last test run	Only the last test run is selected
Test run equals	Only the test run number specified in the numeric field is selected
Test run less than	Only test runs less than test run number specified in the numeric field is selected
Test run greater than	Only test runs greater than test run number specified in the numeric field is selected

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Test Result	Х	
Test Yield	Х	
Test Step Yield	Х	
Test Step Error Pareto	Х	
Test Duration	Х	
Test Step Duration	Х	



4.10 Test step cycle

Limits data so that it only includes data with the selected test step cycle parameter. Test step cycle is defined by how many times an individual test step has reported a result in the same test report

Test step cycle

 Last test step cycle

 All test step cycles

 First test step cycle

 Last test step cycle

Parameters

All test step cycles	Includes all test step cycles in selected data
First test step cycle	Only the first test step cycle is selected
Last test step cycle	Only the last test step cycle is selected

Report	Default filter	Advanced filter
SPC	Х	
Time Series	Х	
Test Step Yield	Х	
Test Step Error Pareto	Х	
Test Step Duration	Х	



4.11 Test stations

Limits data so that it only includes data from the selected test station(s).

By default (*), all items are selected, however this is an inter-related field (see section 4.2), so a selection in one of the other related fields will influence the available contents of the Test stations field.

To select a test station to include, set focus onto the Test stations field by clicking it with the mouse. A list of all available test stations is shown. Select a test station to include by clicking it.

To select more test stations, simply select another test station by clicking it.





To search for a specific test station, simply type any part of the test station name.

Test stations

DK-CIM-00001 x dk-cim	
<u>DK-CIM</u> -00002	^
<u>DK-CIM</u> -00003	
<u>DK-CIM</u> -00004	I
DK-CIM-00005	I
DK-CIM-00006	I
DK-CIM-00007	I
DK-CIM-00008	I
DK-CIM-00009	
DK-CIM-00010	-

Remark

Test stations are not related to specific tests. Therefore, all known test stations can be selected. Since test stations is not a mandatory field, there can be test results without any relation to test station.

Report	Default filter	Advanced filter
SPC		Х
Time Series		Х
Test Result		Х
Test Yield		Х
Test Step Yield		Х
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		Х



4.12 Test fixtures

Limits data so that it only includes data from the selected test fixture(s).

By default (*), all items are selected, however this is an inter-related field (see section 4.2), so a selection in one of the other related fields will influence the available contents of the Test fixtures field.

To select a test fixture to include, set focus onto the Test fixtures field by clicking it with the mouse. A list of all available test fixtures is shown. Select a test fixture to include by clicking it.

Test fixtures	
	Α
	В
	Fixture123
	FixtureA

To select more test fixtures, simply select another test fixture by clicking it.





To search for a specific test fixture, simply type any part of the test fixture name.

Test fixtures

A × 123			
Fixture <u>123</u>			

Remark

Test fixtures are not related to specific test stations, tests etc. Therefore, all known fixtures can be selected.

Since test fixture not is a mandatory field, there can be test results without any relation to test fixture.

Report	Default filter	Advanced filter
SPC		Х
Time Series		Х
Test Result		Х
Test Yield		Х
Test Step Yield		Х
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		Х



4.13 Test version

Filters on the version of the Test software used to test the units (Test sequence version).

By default (*), all test versions are selected.

To select a test version to include, set focus onto the Test version field by clicking it with the mouse. A list of all available test versions is shown. Select a test version to include by clicking it.

Test versions	
	1.050
	1.060
	1.070
	1.080
	1.090
	1.100
	1.110
	1.130
	1.140

To search for a specific test version, simply type any part of the test version name.

Test versions	1.0
	<u>1.0</u> 50
	<u>1.0</u> 60
	<u>1.0</u> 70
	<u>1.0</u> 80
	<u>1.0</u> 90

Remark

Test version is not related to specific tests. Therefore all known test versions can be selected.

Since test version isn't a mandatory field, there can be test results without any relation to test version.



Available in the following report(s)

Report	Default filter	Advanced filter
SPC		Х
Time Series		Х
Test Result		Х
Test Yield		Х
Test Step Yield		Х
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		X

4.14 Test category

Filter on one or more test categories. Test categories can for example be "Production" or "Commissioning". If all real production data is marked with test category "Production", the filter can be used to filter out all data that is not related to units being produced.

Test categories

dministrator	
ST	
ebug	
opsa	
igrated	
roduction	
eqZap	

Note: The filter depends on the availability of test category in the data being imported.

Report	Default filter	Advanced filter
SPC		Х
Time Series		Х
Test Result		Х
Test Yield		Х
Test Step Yield		Х
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		Х



4.15 Measurement range

Measurement range is used to filter numeric measurements. The Min and Max value can be used together or individually.

Measurement range	Min			Max	
-------------------	-----	--	--	-----	--

Example:

Measurements without Min or Max set.

)																		Mea:
))																		+3σ Μeai -3σ USL
0																		LSL
)	<u>a</u> z 2 6	<u>a</u> 2	\$ 2 <u>7</u> 5 \$	2 57 ∆4	8 90	o * 25° :	A	200 2	<u>8</u> 72	2400 2433	<u> </u>	78 <u>2</u> , 2	0 88 0	- 2 2	77 72 7	\$ ` 286	9 <u>7</u> 2	
)																		
0																		

Measurements with Min set to 1.795 and no Max limit.

Measurement range	Min 1.795	Max	
Series Chart			•
Zoom X axis Y axis Both axes	Reset		
1,815 E+00			Measurement

1,805 E+00			
1,800 E+00			
1,795 E+00	***	<u>} 986 200 000 000 000 000 000 000 000 000 00</u>	\$* \$\$\$\$ \$\$\$ \$\$
1,790 E+00			
1,785 E+00			
1,780 E+00			
1,775 E+00			
3915 11.16 00 00 00 00	5016 2 16 00 00 10 10 00 00 00 00 00 00 00 00 00	50603010000 5060360000 50604600000	191 40 40 40 40 40 40 40 40 40 40 40 40 40





Measurements with Min set to 1.795 and Max set to 1.805



Report	Default filter	Advanced filter
Time Series		Х



4.16 Sort by

Used to present data in the Time Series graph, either by time stamp (date) or by serial number. The sorting of serial numbers is handled as texts.



Example of data presented by time:



Same data presented by serial no.:



Report	Default filter	Advanced filter
Time Series		Х



4.17 Serial no. range

Filters on specific serial numbers.

Serial no. range	From serial no.	-	To serial no.

There are two ways to search for serial numbers: Either by filling in only "From serial no." or by filling in both "From serial no." and "To serial no."

From serial no. (only):

The "*" character can be used as a wild card to create a search like this: AT8IN10*HA09. The result of this search will be all the units ranging from AT8IN100000HA09 to AT8IN109999HA09 assuming that is the format of the given serial number.

The "*" can be any character, not only numbers, and any number of characters.

From serial no. and To serial no.:

When using both "From serial no." and "To serial no.", the "*" character cannot be used. Instead, type in two serial numbers like this: From AT8IN100000HA09 to AT8IN109999HA09. The result of this search will be the same as above – all units ranging from AT8IN100000HA09 to AT8IN109999HA09.

Also, the "From – To" search is based on characters, not numbers - so searching like this would also be valid: From AT8IN100000AA09 To AT8IN100000ZZ09.

Report	Default filter	Advanced filter
SPC		Х
Time Series		Х
Test Result		Х
Repair Pareto		Х
Test Yield		Х
Test Step Yield		Х
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		Х



4.18 Unit Revision

Limits data so that it only includes data from the selected unit revision(s).

By default (*), all unit revisions are selected.

To select a unit revision to include, set focus onto the unit revisions field by clicking it with the mouse. A list of all available unit revisions is shown. Select a unit revision to include by clicking it.

Unit revisions	
onit revisions	
	00\r
	0A00
	0A01
	0A04
	0A08
	0A09
	0A10
	0A11
	0A12

To select more unit revisions, simply select another unit revision by clicking it.

Unit revisions	0A00 × 0A04 ×
	00\r
	0A01
	0A08
	0A09
	0A10
	0A11
	0A12
	0A13
	0A14



To search for a specific unit revision, simply type any part of the unit revision name.

Unit	revision

nit revisions	0A00 × 0A04 × 0c
	<u>0C</u> .00
	<u>0C</u> .03
	<u>0C</u> 00
	<u>0C</u> 01
	<u>0C</u> 02
	<u>0C</u> 03
	<u>0C</u> 04
	<u>0C</u> 05
	0C06

Remark

Unit revisions are not related to specific test stations, tests etc. Therefore, all known unit revisions can be selected. Since unit revision not is a mandatory field, there can be test results without any relation to a unit revision.

Report	Default filter	Advanced filter
SPC		X
Time Series		Х
Test Result		Х
Test Yield		Х
Test Step Yield		X
Test Step Error Pareto		Х
Test Duration		Х
Test Step Duration		X



4.19 Item

Limits data so that it only includes data from the selected item.

To select an item to include, set focus onto the Item field by clicking it with the mouse. A list of all available items is shown. Select an item to include by clicking it.

11	0	m	20
	-		10

CIM-100.1043938723
CIM-100.1521232819
CIM-100.1744307622
CIM-100.2744123899
CIM-100.3356852756
CIM-100.4172098942
CIM-100.613163989
CIM-101
CIM-101 1537114716

To search for a specific item, simply type any part of the item number or name.

Items	sim-
	<u>CIM-</u> 100
	<u>CIM-</u> 100.1043938723
	<u>CIM-</u> 100.1521232819
	<u>CIM-</u> 100.1744307622
	CIM-100.2744123899
	<u>CIM-</u> 100.3356852756
	<u>CIM-</u> 100.4172098942
	<u>CIM-</u> 100.613163989
	CIM-101

Available in the following report(s)

Report	Default filter	Advanced filter
Unit Overview	Х	

4.20 Serial no.

Used to find a specific unit. Serial number must be identical to the unit's serial number.

Serial no.

Enter a serial no.



Report	Default filter	Advanced filter
Unit Overview	Х	



4.21 Group by

Group by is used to group presented data.

Group by	Week	•
	Hour	*
	Day	
	Week	
	Month	
	Item	
	Test	
	Test run	
	Test station	
	Test fixture	-

Parameters

Hour	Group data selection in hours
Day	Group data selection in days
Week	Group data selection in weeks (Monday is the first day of the week)
Month	Group data selection in months
Item	Group data selection by item
Test	Group data selection by test
Test run	Group data selection by test run
Test station	Group data selection by test station
Test fixture	Group data selection by test fixture
Test socket	Group data selection by test socket
Test version	Group data selection by test version
Test category	Group data selection by test category
Test operator type	Group data selection by test operator type
Test operator user	Group data selection by test operator user
Order No.	Group data selection by order No.
Unit Revision	Group data selection by unit revision
None	Group data as one selection

Note: A group with no name indicates that the grouped value is missing on values. This is due to how certain properties on result sets are optional. **Available in the following report(s)**

Report	Default filter	Advanced filter
Test Yield	Х	
Test Duration	Х	



4.22 Time element

Time element is used to filter by test and / or handling time.

Time element	Both test and handling time
-	Both test and handling time
	Only test time
	Only handling time

Parameters

Both test and handling time	Shows test time and handling time in selection data result
Only test time	Shows only test time in selection data result
Only handling time	Shows only handling time in selection data result

Available in the following report(s)

Report	Default filter	Advanced filter
Test Duration		Х

4.23 Handling time cutoff

Defines the upper limit of the handling time between two tests. If the time between two tests exceeds handling time cutoff, the handling time is set to the cutoff value.

Handling time cut off

00:15:00

Time is entered as hh:mm:ss (hours : minutes : seconds)

Report	Default filter	Advanced filter
Test Duration		Х



5 System

By selecting System from the menu, the follow page is shown.

FACTS	Dashboard	Reports	System Ad	lministrator 👻
System				Θ
USER MANAGE	MENT			
Users				
Distribution Groups	D8			
Kiosk URLs	þa			
DASHBOARD M				
Dashboard Confi	gurations			
DATA MANAGE	MENT			
Items				
Item Groups				
Panel Configurat	ions			
SERVICE MANA	GEMENT			
Import Tasks				
Import Task Mon	itor			
Scheduled Repo	rts			
Test Mail Setting	S			
Alarm Configurat	ions			
Alarm Monitor				

5.1 User management

Gives access to maintain users and security groups.

5.1.1 Users

Gives a list of all users in the system. Existing users cannot be deleted. If access needs to be restricted/blocked for a certain user, edit the user and uncheck the "Enabled" check box.

FA	∧ , ∩TS	Dashboard	Reports	System					Administrator 🗸
Syst	em / Users								Θ
+	New User								
Q				M 4	Show	ving 1 to 1 of 1 users			
	Enabled	🔶 User	name	≜ F	ull name 🛛 🔶	Last sign in	\$ C	Created	
ß	Yes	admi	n	A	dministrator	2016-05-20 22:09:49	2	013-03-13	



5.1.1.1 Add new user

To add a new user, click the 'New User" button on the Users page. Fill out the fields on the page and click Save.

System / Users / New Us	er	
ACCOUNT		
Enabled	Yes No	
Username		<u>ا</u>
Full name		
Description		
Email address		
Validation type	FACTS 🔻	
Password	۹	
Confirm password	۹	
MEMBERSHIP		
Security groups		

In order to get access to the system, the user must be enabled and be assigned one or more security groups.

Validation type can be set to one of the following:

Validation Type	Description
FACTS	Uses the local FACTS database to store credentials and only validates against this.
Local Machine	Stores username in FACTS database, but validates against the local Windows OS users.
Active Directory	Stores username in FACTS database, but validates against the domain that the current machine is part of. Only available when server is part of a domain .



5.1.1.2 Edit user

To edit an existing user, click the edit icon ${\baselinesises}$ in the user list.

FA CTS Dashbo	woard Reports System	Administrator 🗸
System / Users / Edit Use	ser 'admin'	Θ
ACCOUNT		
Enabled	Yes No	
Username	admin	
Full name	Administrator	
Description	Default administrator user	
Email address	cim@cim.as	
Password	Leave blank to not change password	
Confirm password		
MEMBERSHIP		
Security groups	Administrators ×	
	✓ Save	

When finished editing user settings, click Save to store changes.

5.1.2 Security Groups

Security groups control which pages and items a user is allowed to access.

FA	CTS Dashboard Reports System		Administrator 🗸
Syst	em / Security Groups		9
+	New Security Group		
Q	₩ ◄ ►	Showing 1 to 10 of 10 security groups	
	Name 🔺	Description	
ß	Access to Item group 1		
ß	Administrators	Default administrative user group	
ß	ALT	Accelerated Life Time	
ß	Company AA		
ß	ItemsAndDashboardOnly	Allows access to items and dashboard; nothing else	
ß	Kiosk Group	Access to Dashboard	
ß	No access to Unit / Unit Overview Report		
Q,	PLR All Items	PLR role + full item access	
©.	UnitReports	Has access to unit reports	
ß	Users		

If a user is a member of more security groups, it is the sum of all allowed items and pages that defines the final access rights for the user.



5.1.2.1 Add new security group

To add new security groups, click the "New Security Group" on "Security Group page". Fill in the fields on the page and click Save.

FACTS Dashboard Reports System
System / Security Groups / New Security Group
Name
Description
llearn
Select some users
Accessible item groups
Select some item groups
Allowed permissions
Administrator Brovides full access to all features and all items
Access to all items - Provides access to all items in the system
Access to an items - Provides access to an items in the system Access to an items - Provides access to the Dashboard
SPC Renort - Provides access to the SPC Renort
Time Series Report - Provides access to the Time Series Report
Unit Overview Report - Provides access to the Unit Overview Report
Test Yield Report - Provides access to the Test Yield Report
Test Result Report - Provides access to the Test Result Report
Unit Report - Provides access to the Unit Report
Test Step Yield Report - Provides access to the Test Step Yield Report
Test Step Error Pareto Report - Provides access to the Test Step Error Pareto Report
Test Duration Report - Provides access to the Test Duration Report
Test Step Duration Report - Provides access to the Test Step Duration Report
XY Graph - Provides access to XY Graph Report
Repair Pareto Report - Provides access to the Repair Pareto Report
User Management - Provides access to User Management
Data Management - Provides access to management of item groups etc.
Alarm Configuration - Provides access to Alarm Configuration
Import Tasks - Provides access to configuration of Import Tasks
Import Task Monitor - Provides access to the Import Task Monitor
Paperless Repair - Provides read/write access to Paperless Repair





5.1.2.2 Edit security group

To edit an existing security group, click the edit icon $\[Med]$ in the security group list.

FACTS Dashboard Reports System	Administrator 🗸
System / Security Groups / Edit Security Group 'Users'	9
Name	
Users	
Description	
Users	
Select some users	
Accessible item groups	
Select some item groups	
- Allowed permissions	
Administrator - Provides full access to all features and all items	
Access to all items - Provides access to all items in the system	
Ø Dashboard - Provides access to the Dashboard	
SPC Report - Provides access to the SPC Report	
Image of the series Report - Provides access to the Time Series Report	
Init Overview Report - Provides access to the Unit Overview Report	
Test Yield Report - Provides access to the Test Yield Report	
Test Result Report - Provides access to the Test Result Report	
Init Report - Provides access to the Unit Report	
Test Step Yield Report - Provides access to the Test Step Yield Report	
Test Step Error Pareto Report - Provides access to the Test Step Error Pareto Report	
Test Duration Report - Provides access to the Test Duration Report	
Test Step Duration Report - Provides access to the Test Step Duration Report	
XY Graph - Provides access to XY Graph Report	
Repair Pareto Report - Provides access to the Repair Pareto Report	
User Management - Provides access to User Management	
Data Management - Provides access to management of item groups etc.	
Alarm Configuration - Provides access to Alarm Configuration	
Import Tasks - Provides access to configuration of Import Tasks	
Import Task Monitor - Provides access to the Import Task Monitor	
Paperless Repair - Provides read/write access to Paperless Repair	
✓ Save	

Save stores changes to the security group

Delete removes the security group from all users and deletes the security group from the system. This action may affect the access rights of existing users.

5.1.3 Distribution Groups

Distribution groups control which users are notified in events where alarms are fired.

FA	∧ ∕ ⊤s	Dashboard	Reports	System		Administrator 🗸
Syst	em / Distribu	ition Groups				θ
+ Q	New Distributi	on Group		M •	Showing 1 to 3 of 3 distribution groups	
	Name			Description	1	
ß	Manufacturing	l .		Manufacturi	ng department	
Q.	Research			Research de	epartment	
ß	Software			Software De	avelopment department	



If a user is a member of more distribution groups, they will be notified of all alarms that are sent to any of the distribution groups.

Distribution groups allows external contacts to receive notifications.

5.1.3.1 Add new distribution group

To add new distribution groups, click the "New Distribution Group" on "Distribution Group page". Fill in the fields on the page and click Save.

FACTS	Dashboard	Reports	System				Ac	ministrator
System / Distribu	tion Groups / 1	New Distribu	tion Group					0
Name								
Description								
Users								
Select some user	5							
Email addresses								
				 Θ				
✓ Save								

5.1.3.2 Edit distribution group

To edit an existing distribution group, click the edit icon $\ensuremath{\mathfrak{G}}$ in the distribution group list.

FACTS	Dashboard	Reports	System					Administrator 🗸
System / Distribu	tion Groups / E	dit Distribu	tion Group '	Manufacturing'				Θ
Name Manufacturing								
Description								
Manufacturing de	partment							
Users								
kip ≍								
Email addresses								
cpt@link2it.dk								
					0			
✓ Save	Delete							

Save stores changes to the distribution group

Delete removes the distribution group from all users and deletes the distribution group from the system. This may affect alarm configurations.



5.1.4 Sharing Groups

The Sharing group feature allows the user to create and manage internal groups and to share content such as filter templates, with other group members.

FÆ	ACTS	Dashboard	Reports	System		Administr
Syst	em / Sharing	Groups				
+ Q	New Sharing C	Group		M •	Showing 1 to 4 of 4 sharing groups	
	Name				Description	
ß	Admin Sharing	g Group			Sharing groups for administrators	
ß	Default				Default Group	
ß	KIP				KIP Sharing	
ß	Research Gro	up			Research Group	

With this option, the user is able to create dashboard views by using the shared templates. The feature also allows to generate default dashboards for new users by sharing dashboard views, and subscribe the user to the shared group.

If you want to read more about these FACTS functionalities, go to:

Sharing filter templates 4.1.6

Sharing dashboard view 5.2.2.3

5.1.4.1 Add new sharing group

To add new sharing group, click the "New Sharing Group". Fill the form with a name, description and attach users you want to give access to the shared content. Click save to save the group.

FACTS Dashboard Reports System	Administrator 🗸
System / Sharing Groups / New Sharing Group	Θ
Name	
Description	
Users	
Select some users	
✓ Save	

5.1.4.2 Edit sharing group

To edit an existing sharing group, click the $\[equiverse]$ -icon, in the list of sharing groups.

FACTS	Dashboard	Reports	System									Adm	inistrato	-
System / Sharing	Groups / Edit	Sharing Grou	up 'Admin S	haring Group'										Ð
Name Admin Sharing Gr	oup]									
Description					_									
Sharing groups fo	r administrators													
Users					_									
admin ×														
✓ Save	Delete													

Click save to store the changes.

If you want to remove the sharing group from the system, click delete button.



5.1.5 Kiosk URLs

Kiosk URLs or Kiosk mode allows setting up auto sign-in using specific URLs. Kiosk URLs can be disabled by disabling the user which is used for authorization. Kiosk mode is a way of showing multiple dashboard views, that automatically change at a set interval.

To use kiosk mode, configure a dashboard with the wanted views and widgets, and set up a device to show the kiosk URL.

F/	A ∕ TS □∉	ishboard	Reports	s Sy	stem					Administrator 🗕		
Sys	System / Kiosk URLs											
+ Q	New Klosk URL Showing 1 to 3 of 3 klosk urls											
	Kiosk name	Run as			Kiosk url			Modified	Modified by user			
ß	Ρ	Kiosk U	ser (Kiosk	demo)	http://develop.cim.as	/cpt/head/Dashboard/Kiosk/l	Р	2016-05-19 10:57:00	Anders Meister (Meister)			
Ø	ProductionScreen1	tionScreen1 Kiosk User (Kiosk demo) http://develop.cim.as/cpt/head/Dashboard/Kiosk/ProductionScreen1 2016-05-22 11:45-54 Administrator (admin)										
ß	ProductionScreen2	Kiosk U	ser (Kiosk	demo)	http://develop.cim.as	/cpt/head/Dashboard/Kiosk/l	ProductionScreen2	2016-05-22 11:46:09	Administrator (admin)			

5.1.5.1 Add new Kiosk URL

To add a new kiosk URL, click the "New Kiosk URL" on "Kiosk URLs page". Fill in the fields on the page and click save.

FACTS Dashboard Reports	System	Administrator 🗸
System / Kiosk URLs / New Kiosk URL		0
SETTINGS		
Run as user Kiosk demo	• Ø	
Kiosk name		•
✓ Save		

5.1.5.2 Edit kiosk URL

To edit an existing kiosk URL, click the edit icon 🧉 in the kiosk url list.

FACTS Dashbo	ard Reports	System		Administrator 👻
System / Kiosk URLs / Ed	it Kiosk URL 'Pro	ductionScre	en1'	0
SETTINGS				
Run as user	Kiosk demo		- O	
Kiosk name	ProductionScree	en1		D
	✓ Save	🛍 Delete		

Save stores changes to the kiosk URL.

Delete removes the kiosk URL from the system. This may affect any devices configured to automatically sign on, using a kiosk URL.



5.1.5.3 Play and pause in Kiosk

If you want to have a closer look on a specific view while the kiosk views are rolling, you can simply pause the carousel view, by clicking the pause button in the upper-right corner.

FACTS	Dashboard	Reports System					×
★ Most Teste	I		C	★ Worst Yield			
Item	Test	Tests	Yield	Item	Test	Tests	
No results with	current settings.			No results with current se	ttings.		
Dashboard info 14:25:46. Items	rmation for the pa with less than 50	st 30 days created 201 0 tests excluded.	7-09-08	Dashboard information for	the past 30 days created 2017-09-08 14:2!	5:48. Items with less than 500 tests excluded.	

5.1.5.4 Automatically open kiosk URLs

It is possible to open a kiosk URL in full screen mode, using either Internet Explorer or Google Chrome. Microsoft Edge does not support full screen at the moment, but kiosk URLs will still work with it.

5.1.5.4.1	Internet E	xplorer
0.1.0.1.1	Internet B	apioi ci

💋 Egenskaber for FACTS Kiosk			
Generelt Genvej Sikkerhed Detaljer Tidligere versioner			
FACTS Kiosk			
Type: Program			
Placering: Internet Explorer			
Destination: xplorer\iexplore.exe" + http://example.com/fact	s		
Start į: "C:\Program Files (x86)\Internet Explorer"			
<u>G</u> envejstast: Ingen			
Kø <u>r</u> : Normalt vindue 🗸 🗸			
Kommentar:			
Åbn filplacering Skift ikon Avanceret			
OK Annuller An <u>v</u>	end		

To automatically open a page in full screen, using internet explorer, create a shortcut with the following destination:



"C:\Program Files (x86)\Internet Explorer" -k <u>http://example.com/facts</u>

Be sure to keep quotes intact and modify the path to internet explorer in case you are using a pc with a 32bit OS installed. Change <u>http://example.com/facts</u> to be the kiosk url you configured in the web interface.

Figenskaber	for FACTS	Kiosk		×
Cildenhad Detailor Tidligger versions				
Generelt		Genvej	Kompatibi	litet
s e	ACTS Kiosk			
Туре:	Program			
Placering:	Application	ı		
Destination: on\chrome.exe"kiosk http://example.com/facts				
Start į: "C:\Program Files (x86)\Google\Chrome\Applicati				
<u>G</u> envejstast: Ingen				
Kø <u>r</u> :	C Normalt vindue ~			
Kommentar:				
Å <u>b</u> n filpla	cering	<u>S</u> kift ikon	A <u>v</u> anceret	
		ОК	Annuller	An <u>v</u> end

To automatically open a page in full screen, using Google Chrome, create a shortcut with the following destination:

"C:\Program Files (x86)\Google\Chrome\Application\chrome.exe" --kiosk <u>http://example.com/facts</u>

Be sure to keep quotes intact and modify the path to Google Chrome in case you are using a pc with a 32bit OS installed. Change <u>http://example.com/facts</u> to be the kiosk url you configured in the web interface.

5.2 Dashboard

The personal dashboard requires some configuration by a user, but allows quick overview of what is going on in FACTS.



The personal dashboard is printable, but not exportable to excel. A small in the top-right corner, left of the users name, allows users to print their dashboard.



5.2.1 Settings

The settings page contains settings that are used for the dashboard and when in kiosk mode.

FACTS Dashboard Reports System	Administrator 🗸
System / Dashboard Configuration	Θ
KIOSK MODE	
Loop interval (seconds) 15 Data refresh rate (minutes) 5	
VIEWS	
Active Views (drag to reorder)	
Dashboard ×	
✓ Save	
✤ New Dashboard View	
Q Showing 1 to 1 of 1 Dashboard Views	
Name A Description	
G Dashboard Standard dashboard. Includes the Most Tested and Worst Yield widgets.	

5.2.1.1 Kiosk mode

Loop interval is the time (in seconds) between views, when logged into kiosk mode. This time is a minimum value, as the actual time is (time taken to load any data, if needed) + value.

Data refresh rate defines how long FACTS caches any results loaded in both the ordinary dashboard and in kiosk mode. While data is cached and within the refresh rate, the loop interval between views, will remain the value specified.

5.2.1.2 Views

Views allows specifying which views are shown on the dashboard and in which order the kiosk will switch between them.

To remove a view from the list, click the "X".



To add a view to the list, click it and pick from the available views.

Dashboard	

Items can be arranged by drag and drop to select the order in which they are shown.



5.2.2 Dashboard Views

Dashboard views specify a logical grouping of widgets. They allow users to create their own personal dashboards. By default, a user will have a single dashboard view, with 2 widgets, "Most Tested" and "Worst Yield". This can be customized.

5.2.2.1 Add new dashboard view

To add a new dashboard view, click the "New Dashboard View" button. Fill out the fields on the page and click Save.

FACTS Dashboa	rd Reports System	Administrato
System / Dashboard Configu	ration / New Dashboard Vie	W
DETAILS		
Name		
Description		
WIDGETS		
	+ Add Widget	
	✓ Save	

5.2.2.2 Edit dashboard view

To edit an exis	sting dashboard vie	w, click the edit	: icon 🤷 in the i	tem list.	
	oard Reports System				Administrator 🚽
System / Dashboard Config	gurations / Edit Dashboard View 'Dash	board'			Θ
DETAILS					
Name	Dashboard]	
Description	Standard dashboard. Includes the 'Most Tested' and 'Worst Yield' widgets.]	
Sharing Groups]	
WIDGETS					
	+ Add Widget				
	¢ ⁸ System Status		Youtube		
	★ Sample	★ Worst Yield	Rest Yield		
	✓ Save 🛍 Delete				

5.2.2.3 Sharing dashboard view

To add the selected view in one or more sharing groups, click in the sharing group field to get a list of groups. Note that only the groups you are attached to will appear in the list. Select the groups you want to share with, and click save.

New users created, with the selected sharing groups, will get the shared views as their default views.


OBS. The shared views will not appear in the dashboard view list for the members of the groups. This functionality is only for pre-generating a set of views, for new users.

5.2.3 Widgets

Widgets display information and can be arranged in many different configurations. Each widget is its own little container of information.

5.2.3.1 Add new widget

To add a new widget, edit an existing dashboard or create a new one, and click the "Add Widget" button.

Widget configuration			
Name Widget type	Select a widget		
		OK Cancel	

Fill in the fields. The available fields, change depending on the selections done to "Widget type".

5.2.3.2 Edit existing widget

To edit an existing widget, hover over it and click the edit icon. This will open the configuration dialogue.



Changes to widgets are only saved, when the view is saved.

5.2.3.3 Deleting an existing widget

To delete an existing widget, hover over it and click the delete icon. This will remove the widget from the view.



Widgets removed, are only saved when the view is saved.



5.2.3.4 Arranging widgets

Widgets are layed out in a grid with 6 columns. Widgets can be resized to take up between 1 and 6 columns. A single row can contain widgets that total up to 6 columns. This allows for multiple configuration options, such as 1 widget of 6 columns, 2 widgets of 3 columns each or 1 widget of 2 columns, 1 widget of 3 columns and a single widget of 1 column.

A row does not need to be filled. Rows cannot be skipped.

To resize a widget, click the handles in the bottom corners of it.



To move the widget to a new location, click the widget and drag and drop to the new location. Dragging downwards, outside the box, will add a new empty row to add the selected widget to.

5.2.3.5 Widget types

There are 10 widget types. Each serves a different purpose.

5.2.3.5.1 WebView

The WebView type allows embedding an external web page into FACTS.

Typical use:

Embed external search or adding information from other systems.

Widget configuration *					
Name					
Widget type	WebView -				
URL	Include http:// or https://				
Height (pixels)	400				
		OK Cancel			

URL is the address of the page that is to be embedded

Height specifies the height on the dashboard. If the height of the widget is less than the webpage, a scrollbar will be visible. If it is larger than the webpage, blank space will be shown. This is the only widget that allows specifying a height.

5.2.3.5.2 Most Tested

Displays the most tested items. Users can specify the number of required tests and the time period in their user settings.

Widget configuration *					
Name Widget type	Most Tested 💌				
		OK Cancel			

5.2.3.5.3 Worst Yield

Displays the worst yields. Users can specify the number of required tests and the time period in their user settings.

Widget configuration ×				
Name Widget type	Worst Yield •			
		OK Cancel		

5.2.3.5.4 Best Yield

Displays the best yields. Users can specify the number of required tests and the time period in their user settings.

Widget configuration *				
Name Widget type	Best Yield 💌			
		OK Cancel		



FA CTS



5.2.3.5.5 Image Widget

Allows for adding a custom image to a dashboard.

Images can be aligned to the left or to the right, or be set to fill the space available.

Typical use: insert company logo for printed reports/dashboards.

Widget configuration				
Name		Å		
Widget type	Image	-		
URL	Include http:// or https://			
Alignment	Select an image alignment.	•		
		۹		
	Left		ОК	Cancel
	Right			
	Fill			

5.2.3.5.6 Youtube Widget

Displays a youtube video. Videos are automatically paused in kioskmode, while they are offscreen. Simply copy the video ID from the youtube page and past it in the Video ID field, to add a video to the dashboard.

Widget configuration ×				
Name	1 1			
Widget type	Youtube			
Video ID	bHQqvYy5KYo			
		OK Cancel		



5.2.3.5.7 Text Widget

Allows for adding custom, formatted text to the dashboard. **Typical use:** insert standard text for a printed report/dashboard.

Widget configur	ration ×	
Name Widget type	Text -	
Sorrats -	B I ≣ ≣ ≣ ■	
р		
	OK Cancel	



5.2.3.5.8 Report Widget

Report widgets are based on a user's filter templates. They allow embedding reports on the dashboard.

Widget configuration				
Name				
Widget type	Report Widget	•		
Filter template	Select a Filter template	•		
Report type	Select a report type	•		
Data type	Select a data type	•		
			OK	Cancel
			UN	Cancer

Depending on the type of filter used, different Data type options will be available.

Data type	Select a data type	•
		Q
	Data Table	
	Chart	

Report	Datatable	Chart	Distribution Chart	Series Chart	Test Overview	Test Step Results
SPC	Х					
Time Series	Х		Х	Х		
Test Result	Х					
Repair Pareto	Х	Х				
Test Yield	Х	Х				
Test Step Yield	Х	Х				
Test Step Error	Х					
Pareto						
Test Duration		Х				
Test Step	Х					
Duration						
Unit Overview					x	Х



5.2.3.5.9 Image Slider Widget

The Image slider widget are made to read and display images from a folder.

Widget configuration				
Name	Slider			
Widget type	Image Slider	•		
Path	C:\Users\xxxx\Desktop\Images			
Image refresh (ms)	2000			
	Carousel	•		
			OK-	Cancol
			UK	Cancer

The widget has two display types (*Latest, Carousel*), and a refresh interval that defines how often you want the widget to read and update from the defined path.

The Latest mode, always shows the latest created image in the folder.

The *Carousel* mode will automatically show the images in a loop, when the last image is shown.

5.2.3.5.10 Service Status Widget

The service status gives you a status overview of the FACTS services.

Service Status						
Showing 7 statuses						
Service 🔺	Name 🔺	Status 🔶	Message			
Alarm Service	CPT.AlarmService.TestResults	Idle				
Importer Task	CPT.TestResultSimulator	Stopped	Importer stopped!			
Importer Task	CPT.TestStand.Logger	Stopped	Importer stopped!			
Importer Task	CPT.TestStation.Client	Stopped	Importer stopped!			
Importer Task	DIV.TestData	Stopped	Importer stopped!			
Importer Task	Grundfoss Test Importer	Stopped	Importer stopped!			
Importer Task	TestStand XML	Stopped	Importer stopped!			

The widget will simply list the different services with a message and status. The service requires no configuration but a widget-name.



5.3 Data management

Provides functions to control and manage items.

5.3.1 Items

Define the relations between item numbers/identifiers and their item names. Item names are used as an alias for item numbers to make items easier to recognize and filter out.

F/	A C TS	Dashboar	d Reports	System		
Sys	tem / Items					
Q	CIM			M A M Showing 1 to 25 of	9,203 items (filtered from 20),018 total items)
	Number		Name		\$ C	reated 🔶
ß	10002-043	1	Name with "spec	ial" characters <> æøåÆØÅ - Инструменты CIM	Производство 2	013-10-20 13:17:14
ß	CIM-100				2	013-12-13 16:18:35
ß	CIM-100.10439	38723			2	013-12-13 15:54:12

5.3.1.1 Edit items

To edit an existing item number / name relation, click the edit icon $\ ^{m{arepsilon}}$ in the Item list.

FACTS Dashboard Reports System	Administrator 🗸
System / Items / Edit Item 'CIM-100'	0
Item number CIM-100	
Item name	
Enter a name for the Item	
✓ Save	

Save stores the changes to the item name.

5.3.2 Item Groups

Defines the grouping of items. Item groups can be used to control item access rights for user groups.

FA	CTS Dashboard Reports System		Administrator 🗸				
Syst	System / Item Groups						
+	✤ New Item Group						
Q	₩ ◄ ►	Showing 1 to 5 of 5 item groups					
	Name	Description					
ß	Atex items	Items that belongs to Atex					
ß	Customer A						
ß	Customer B						
ß	External Consultants						
ß	Special Customers	10005-043					

5.3.2.1 Add item groups

To add a new item group, click the "New Item Group" on the "Item Groups page". Fill in the fields on the page and click Save.



FACTS	Dashboard	Reports	System		
System / Item Gr	oups / New Ite	em Group			
Name					
Enter a name					
Description					
Itoms				7	
Coloct one or more	itoma				
Select one or more	e items				
✓ Save					

5.3.2.2 Edit item groups

To edit an existing item group, click the edit icon $\ensuremath{\sigma}$ in the Item Group list.

FACTS Dashboard Reports System	Administrator 🗸
System / Item Groups / Edit Item Group 'Atex items'	0
Name	
Atex items	
Description	
Items that belongs to Atex	
Items	
403503A - Atex Battery Primary ×	
✓ Save 📋 Delete	

Save stores the changes to the item group.

5.3.3 Panel configuration

Used to configure the layout of panels. Panels are used to group several DUTs under one barcode in PLR (Paper less repair).

F/	ACTS Dashboard	Reports	System		
Sys	tem / Panel Configuration				
È.	New Panel configuration				
_	r rener configuration				
Q			HE 4	► ₩ Showing 1 to 7 of	7 panels
	Name			Modified	Modified by user
ß	Standard2x2			2016-05-22 09:39:14	Administrator (admin)
	n vermennen.			Concerned to reach the second second	
ß	Ints2x2			2016-05-22 09:39:12	Administrator (admin)
S S	Admintest			2016-05-22 09:39:12 2016-05-22 09:38:35	Administrator (admin) Administrator (admin)
0 0 0	Admintest at2x2			2016-05-22 09:39:12 2016-05-22 09:38:35 2016-05-22 09:38:29	Administrator (admin) Administrator (admin) Administrator (admin)
<u>ର</u> ର ର	Admintest at2x2 New			2016-05-22 09:39:12 2016-05-22 09:38:35 2016-05-22 09:38:29 2016-05-22 09:38:25	Administrator (admin) Administrator (admin) Administrator (admin) Administrator (admin)
0 0 0 0 0 0 0	Ints2x2 Admintest at2x2 New AddedPanel			2016-05-22 09 39:12 2016-05-22 09 38:35 2016-05-22 09 38:29 2016-05-22 09 38:25 2016-05-22 09 38:25	Administrator (admin) Administrator (admin) Administrator (admin) Administrator (admin) Administrator (admin)

5.3.3.1 Add panel configuration

To add a new panel configuration, click the "New Panel configuration" on the "Panel configuration page". Fill in the fields on the page and click Save.

Changes to the "Columns" and "Rows" fields will redraw the panel layout and default the value of the layout fields.



FACTS Dashbox	ard Reports	System		Administrator -
System / Panel Configuration	New Panel co	onfiguration		Θ
CONFIGURATION				
Name Columns Rows PANEL LAYOUT [COL-ROW]	UserGuidePane			
BC	✓ Save			

5.3.3.2 Edit panel configuration

To edit an existing item group, click the edit icon $\ ^{\ }$ in the Item Group list.

	erd Reports System Adminis	strator 👻
System / Panel Configuration	n / Edit Panel 'UserGuidePanel'	Θ
CONFIGURATION		
Name	UserGuidePanel	
Columns	1	
Rows	3	
PANEL LAYOUT [COL:ROW]		
A		
В		
C		
	Savo 🔒 Delete	

Save stores the changes to the item group. Delete is only enabled if no DUTs has been connected to the panel configuration.

5.4 Importer

5.4.1 Import Tasks

By default, the SPC system supports TestStand XML format. Additional import readers can be implemented to support the specific customer needs and business models. In general, test data imports originate either from files like TestStand XML, CSV files etc., or from some different kinds of databases, like MySQL, MS Access, MS-SQL etc. Additional import read can be implemented for both new file formats and data stored in databases.

FA	Ҁтѕ	Dashboard Report	s System					Administrator 🗸
Syst	Jystem / Import Tasks							
+ Q	New File Import Task New Database Import Task New MS Access Import Task New MS Access Import Task Showing 1 to 4 of 4 import tasks							
	Enabled 🚽	Name 👙	Description	Reader 🔶	Plugin	Modified	Modified by	
ß	Yes	CPT.TestResultSimulator		CPT Test Data XML File		2016-04-21 18:18:12	Per Clausen (pcl)	
Ø	Yes	CPT.TestStand.Logger		CPT Test Data XML File		2016-04-26 12:39:23	Per Clausen (pcl)	
ß	Yes	CPT.TestStation.Client		CPT Test Data XML File		2016-02-25 09:20:05	Rasmus Toftdahl Olesen (rto)	
ß	Yes	TestStand XML		CPT TestStand XML File		2015-07-03 09:03:39	Administrator (admin)	

5.4.1.1 Edit an existing import task

To edit an existing data importer task, click the edit icon 🧉 in the importer task list.



FACTS Dashbo	ard Reports System	Administrator
System / Import Tasks / E	dit File Import Task	ହ
GENERAL		
Enabled	Yes No	
Name	CPT. TestResultSimulator]
Description		
Max, test results per unit	25	2
DEFAULTS		_
Item number		0
Test name		0
Test station		0
Test fixture		Θ
TEST RESULT FILES		
Reader	CPT Test Data XML File	Θ
Plugin	None	Θ
Pickup files from	C:\CPT\CPT.TestResultSimulator\Pickup	e
FILE HANDLING OPTIONS		
	✓ Delete imported files	
	✓ Zip imported files to save space	
Move imported files to	C:\CPT\CPT.TestResultSimulator\Imported	Θ
	Delete files with error	
Maura filma urita arreata	Zip mes with end to save space	
move mes with effor to		

"Save" stores the changes to the importer task.

"Delete" deletes and disables the importer task permanently (all parameters will be lost)

5.4.1.2 Creating a new file import task

To setup the necessary parameters for importing test data from a file, the button "New File Import Task" should be clicked.



FACTS Dashbo	ard Reports System	Administrator
System / Import Tasks / N	lew File Import Task	0
GENERAL		
Enabled	Yes No	
Name	Enter a name]
Description		
Max test results per unit	25	2
max. coer rooato por ante		
DEFAULTS		7
Item number		0
Test name		Θ
Test station		Θ
Test fixture		Θ
TEST RESULT FILES		
Reader	CPT Test Data XML File	0
Plugin	None	e
Pickup files from	Enter a path	0
FILE HANDLING OPTIONS		
	Delete imported files	
	Zip imported files to save space	
Move imported files to		Θ
	Delete files with error Zin files with error to save space	
Move files with error to		
Move mes with effor to		J •
	d Saus	
	✓ Jave	

All necessary parameters should be filled out before saving and enabling the new file importer task.

Additional help for each parameter is displayed when moving the mouse pointer over the question mark to the right of each parameter field.



5.4.1.3 Creating a new database import task

To setup the necessary parameters for importing test data from a database, the button "New Database Import Task" should be clicked.

FACTS Dashbo	ard Reports System		Administrator v
System / Import Tasks / N	lew Database Import Task		Θ
GENERAL			
	Mar. No.		
Enabled	Yes No		1
Name	Enter a name		
Description			
Max test results per unit	25 0		
DEFAULTS			
Item number			Θ
Test name			Θ
Test station			•
Test fixture			0
DATABASE SETTINGS			
Reader		-	
Plugin	None	•	Θ
Server			•
User			
Password			
Catalog] 0	
outulog] -	
	✓ Save		

All necessary parameters should be filled out before saving and enabling the new database importer task.

Additional help for each parameter is displayed when moving the mouse pointer over the question mark to the right of each parameter field.



5.4.1.4 Creating a new MS Access import task

To setup the necessary parameters for importing test data from a Microsoft Access database, the button "New MS Access Import Task" should be clicked.

FACTS Dashboa	rd Reports System	Administrator 🗸
System / Import Tasks / N	w MS Access Import Task	0
GENERAL		
Enabled	Yes No	
Name	Enter a name	
Description		
Mary Area In the Sta		
max. test results per unit	20 V	
DEFAULTS		
Item number		9
Test name		9
Test station		9
Test fixture		9
MICROSOFT ACCESS		
Reader		
Plugin	None Contraction C	9
	Open the database in exclusive mode	
Database file path		0
	✓ Save	

All necessary parameters should be filled out before saving and enabling the new MS Access importer task.

Additional help for each parameter is displayed when moving the mouse pointer over the question mark to the right of each parameter field.



5.4.2 Import Task Monitor

This screen is used to investigate the status and error log of the enabled data importers. It contains relevant information and performance indicators to provide an overview to the health of the data import into the system. The information in the screen is automatically updated every 10 seconds.

tem / import	Task Mo	onitor										
Status												
howing 4 impor	rt tasks											
Timestamp		lame		State	Message	Last import 🍦	Last import error 🝦	Avg. import time 🝦	Total imports 🝦	Total import errors	Details	
016-05-20 14:	38:53 C	PT. TestResultSin	nulator	Idle	No data pendin	g 2016-05-20 14:37:22	2016-03-24 01:32:33	118 ms	540.288	278		
016-05-20 14:3	38:53 C	PT.TestStand.Lo	gger	Idle	No data pendin	g 2014-05-14 10:29:11	2014-05-14 10:21:55	103 ms	114.120	147		
016-05-20 14:3	38:53 C	PT.TestStation.C	lient	Idle	No data pendin	g 2016-05-20 07:31:53	2016-05-19 23:42:07	114 ms	8.294	3.528		
016-05-20 14:3	38:53 T	estStand XML		Idle	No data pendin	g 2016-04-29 12:53:22	2016-02-25 15:39:06	746.856 ms	95	14		
L			ŀ	((• •	Showing 1 to 25 of	f 1,000 import task erro	ors				
	Name		Frror ty	mo								
imestamp 🔻			,	he	E	ror message				De	etails	
imestamp _v 016-05-19 3:42:07	CPT.Te	stStation.Client	TestRes	sultVali	dationFailed Te	rror message est.Name cannot be null	or an empty string. Uni	it.SerialNo cannot be n	ull or an empty stri	ng. 44	etails ileName": "201 4203_0d06091 93-9be7- 866b08393b.Cl	60519 b-418 PT.xm
imestamp v 2016-05-19 3:42:07 2016-05-19 2:42:07	CPT.Te	stStation. Client	TestRes TestRes	ultValio sultValio	dationFailed Te	rror message Ist. Name cannot be null Ist. Name cannot be null	or an empty string. Uni or an empty string. Uni	it.SerialNo cannot be n it.SerialNo cannot be n	null or an empty stri null or an empty stri	ng. 44	etails ileName": "2011 4203_0d06091 93-9be7- 866608393b. Cl ileName": "2011 4152_267f5f33 Id2-83bf- 391e255422. C	60519 b-418 PT.xm 60519 3-1de3 PT.xn

5.5 Scheduled Reports

Scheduled reports are used to send out predefined reports at a specified time and with a specified frequency. Reports are sent out by e-mail to predefined receivers. The layout of the scheduled reports is chosen among the existing reports (Test Yield report and Test Step Error Pareto report).

FA	С тѕ	Dashboard Reports	System				Administrator 🗸
Syst	em / Schedu	iled Reports					9
+ Q	New Schedule	ad Report	Showing 1	to 25 of 511 scheduled	reports		
	Enabled _w	Name 🔺	Description	Run as	Modified 🍦	Modified by	
Q.	Yes	Daily Test Step Error Pareto	90 days back. Sent out on weekdays	Administrator (admin)	2016-05-20 14:33:55	Administrator (admin)	
Q.	No	Test Step Error Pareto Report	Test Step Error Pareto	Per Clausen (pcl)	2016-04-28 14:48:48	Per Clausen (pcl)	
Q.	No	Test Step Error Pareto Report	Test Step Error Pareto	Per Clausen (pcl)	2013-10-30 00:44:00	Per Clausen (pcl)	

5.5.1 Adding and Editing scheduled reports

To edit an existing scheduled report, click the edit icon $\[Member \]$ in the scheduled report list. To add a new scheduled report, click "New Scheduled Report"

"Save" stores the changes to the importer task.

"Delete" deletes and disables the scheduled report permanently (all parameters will be lost). "Delete" is only available when editing an existing scheduled report.



5.5.1.1 Settings, Recipients and Recurrence

FACTS Dashbo	pard Reports	System	Administrator -
System / Scheduled Report	ts / Edit Sched	uled Report	Θ
Settings, Recipients and R	lecurrence	port and Filter	
Enabled	Yes No		
Time of day	08:00	▼ 0	
Name	Daily Test Ste	p Error Pareto	
Description	90 days back Sent out on w	eekdays	
		A	
RECIPIENTS			
Users	kip ×		
Email addresses	jba@cim.as	٩	
RECURRENCE			
Start date	2016-05-20	Θ	
Pattern	Daily	Every weekday -	
	Weekly		
	Monthly		
	✓ Save	Delete	
General Setting	<u>s:</u>		
Enabled:		Used to enable or disable the scheduled report generation	
Time of day	y:	The time of day to send out the report	
Name:		Descriptive name of the report	
Descriptior	ו:	Further detailed description for the report	
<u>Recipients:</u>			
Users:		List of system users to receive the report	
E-mail addı	resses	Additional recipients of the report (unknown to the system)	
<u>Recipients:</u>			
Start date:		The begin date for the scheduled reports	
Pattern:		See further descriptions below	

Pattern Daily	Every weekday	•
Weekly		
Monthly		

The "Daily" pattern is used if the report should be sent out on a daily basis (every day or every weekday)

FACTS



The "Weekly" pattern is used if the report should be sent out on certain days of the week.



The "Monthly" pattern is used if the report should be sent out on certain days of the month.

5.5.1.2 Repor	t and Filter	Administrator –
FAL IS Dashood		
System / Scheduled Reports	Edit Scheduled Report	0
Settings, Recipients and Re	currence Report and Filter	
Туре	Test Step Error Pareto Report	
Run as user	lgb 🗸	
Document type	PDF Excel PDF and Excel	
FILTER		
Time period	90 days back 👻	
Items	1	
Tests	•	
Test run	First test run	
Test step cycle	Last test step cycle	
Test stations	•	
	✓ Save	

General Settings:

Type:

The layout of the report to send out (Test Yield or Test Step Error Pareto)



Run as user:The user profile to be used when generating the scheduled reportsDocument type:Send out the report as PDF, Excel or both

Filter:

Set all parameters for the selected report type to obtain the required data in the scheduled reports. Please refer to the sections describing the reports (section 3.9 or section 3.11)

5.6 Test Mail Settings

Test Mail Settings can be used to verify the mail settings are correct in the config file. The mail settings are used by the scheduler service.

FACTS Dashboard Reports System	Administrator +
System / Test Mail Settings	0
Email address	
✓ Send test message	

5.7 Alarm Configuration

Alarm configuration is used to setup notifications when events that are generally considered bad, occurs. These events can be based on different criteria, such as following the WECO rulesets or custom limits for test results. Notifications are sent to distribution groups according to the configured frequency.

FA	C TS	Dashboard	Reports	System				Administrator 🗸
Syst	em / Alarm	Configuration						0
+ Q	New Test Al	arm Configuratio	on	₩ 4	Showing 1 to 5 of 5 configurations			
	Enabled	Alarm type 👙	Name		Description	Modified	Modified by	
G.	Yes	Test step	WRT54B - H	ome Router	WRT54B- Home Router - Notify on power measurement outside range	2016-08-11	Administrator (admin)	
G.	Yes	Test step	CIM-100 Mot	herboard	Firmware Alarms	2016-08-11	Administrator (admin)	
ß	Yes	Test step	Meister Alarr	n	demo settings	2016-08-11	Administrator (admin)	
ß	Yes	Test step	step newitem	11		2016-08-11	Administrator (admin)	
ß	Yes	Test step	newitem2			2016-08-11	Administrator (admin)	

5.7.1 Adding and Editing alarm configurations

To edit an existing alarm configuration, click the edit icon $\[Government]$ in the alarm configuration list. To add a new alarm configuration, click "New Test Alarm Configuration". "Save" stores the changes to the alarm configuration task. "Delete" deletes and disables the configuration permanently (all parameters will be lost). "Delete" is only available when editing an existing alarm configuration.

5.7.2 Test Alarm Configuration

Test Alarm Configuration is a type of alarms configured on a test level.

They require an item and a test to be specified, before allowing you to added specific criteria on each test step.

FACTS

stem / Alarm Config	uration /	Edit Test A	larm Confi	guration 'C	IM-100 Mot	therboard'						(
TTINGS												
Enab	led Y	'es No]									
Na	me Cl	M-100 Moth	ierboard									
Descrip	tion Fi	rmware Alar	ms									
It	em C	IM-100								× •		
T	est C	omputer Mo	therboard Te	est Sequence	ce Loop (Ma	inSequence	e)			× •		
Notification inte	val O	ver the last	5 minutes	•								
Test re	sult A			•								
]							
NFIGURATION												
	S	elect a Test	Step							• + A	dd Test Step	
itep	Туре	Weco 1	Weco 2	Weco 3	Weco 4	Weco 5	Weco 6	Cp < X	Cpk < X	X < limit	X > limit	
	Enable											
PU Diagnostics	Value							1	1	0	10	
	Enable											
PU Test	Value							1	1	0	10	×
lainSequence:\/ideo	Enable											
est	Value							1	1	50	5	×
												_
CIPIENTS												
Distribution gro	ups	oftware ×										

After an item and a test has been selected, individual test steps can be added to the list of checks. Each test step can then have their own set of rules.

- WECO 1: An alarm will be generated if value is outside 3σ
- WECO 2: 2 out of 3 consecutive points fall beyond the 2σ limit
- WECO 3: 4 out of 5 consecutive points fall beyond the σ limit
- WECO 4: 9 consecutive points fall on the same side of the center
- WECO 5: 9 consecutive points are increasing or decreasing
- **WECO 6**: An alarm will be generated if 9 consecutive points shift between increasing and decreasing
- Cp < X: An alarm will be generated if the calculated Cp is less than the specified value
- Cpk < X: An alarm will be generated if the calculated Cpk is less than the specified value
- X < Limit: An alarm will be generated if the tested value is less than the specified limit
- X > Limit: An alarm will be generated if the tested value is greater than the specified limit



5.8 Alarm Monitor

The Alarm monitor is used to track the status of the Alarm service and shows a log of up to 1000 alarms.

ACTS Dashbo	ard Reports System				
stem / Alarm Monitor					
≡ Status					
Showing 1 alarm tasks					
Timestamp	Name	٨	State	Message	Latest test result id
2016-08-11 15:21:50	CPT.AlarmService.TestF	Results	Idle		1155661
Automatically updated eve	rv 10 seconds				
Alarms					
-					
Q	► MI	► ₩ Showir	ng 1 to 25	of 157 alarms	
Timestamp	Configuration name	Description			
2016-08-11 13:51:42	CIM-100 Motherboard	LimitRule: numeric valu	e 5.000 E	+00 is below 50	.000 E+00
2016-08-09 21:51:45	CIM-100 Motherboard	LimitRule: numeric valu	e 5.007 E	+00 is above 5.	000 E+00
2016-08-09 21:51:45	CIM-100 Motherboard	LimitRule: numeric valu	e 5.007 E	+00 is below 50	.000 E+00
2016-08-09 08:25:34	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
2016-08-09 08:25:34	newitem2	WECO 4: 9 consecutive	e points fa	alls on the same	side of the center
2016-08-09 08:25:34	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
2016-08-09 08:25:34	newitem2	WECO 4: 9 consecutive	e points fa	alls on the same	side of the center
2016-08-09 08:25:34	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
2016-08-09 08:25:34	newitem2	WECO 4: 9 consecutive	e points fa	alls on the same	side of the center
2016-08-09 08:25:33	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
2016-08-09 08:25:33	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
2016-08-09 08:25:33	newitem2	WECO 5: 9 consecutive	e points a	re increasing or	decreasing
				0	-



5.9 GAUGE R&R

GAUGE R&R configuration is used to setup color warnings on the Gauge R&R main page. Color warnings are set up per column.

5.9.1 Warning levels

It is possible to set color warnings on each column ('% Study VAR Total Gauge R&R', '% Study VAR Repeatability' and '% Study VAR Reproducibility'). These warnings are triggered if the value exceeds the value set up in the Warning levels settings. If there is no warning value set on a column ('% Study VAR Total Gauge R&R', '% Study VAR Repeatability' or '% Study VAR Reproducibility'), then warning for the column is disabled.

System / Warning levels	
+ New warning	
Q	▶ ₩ Showing 1 to 2 of 2 Warnings
Name	A Value
G % Study VAR Repeatability	40
G % Study VAR Total Gauge R&R	81

% Study VAR Repeatability					
Value					
40					
Save Delete					

6 Personal settings

6.1 Settings

To edit personal settings, select 'User name' to the right in the menu bar and click Settings. (In the example below, the user name is "Administrator")



FACTS Dashboar	d Reports System Administrator
Edit Personal Settings	0
DASHBOARD SYSTEM WIDGET	3
Days back in time	30
Minimum number of tests	100
REPORT FILTER DEFAULTS	
Test categories	
Test operator types	
PRESENTATION	
Table page size	25 rows
Number format	Danish (Denmark)
ACCOUNT	
New password	Leave blank to not change password
Confirm password	
	✓ Save

Dashboard Settings:

Days back in time:	Number of days to look back in Dashboard reports
Minimum number of tests:	The number of tests required to qualify for appearance on the dashboard
Presentation Settings:	
Table page size:	Specifies the number of rows per page in reports presenting data in grids (tables).
Number format:	Specifies how numeric measurements are presented
Account Settings:	
New password:	Used to set a new user password
Confirm password:	Used to set a new user password. Must be identical to "New password"

Save button stores changes.

6.2 Sign out

Sign out, and present the sign in page.



7 License

FACTS requires a license to run. This license is used to determine which products are enabled for the installation. To edit the license select the FACTS logo in the upper left and click "License Management". The window shows an input field to type in the license key, and information about the current license.

FACTS Sign in		
License		0
Key License key ✓ Save		
Licensed to:	eCim Development	
License type:	Registered	
Enabled products:	Importer service Alarm service Scheduler service Paperless repair Facts: Administrator Facts: Report - Time Serles Facts: Report - Nint Serles Facts: Report - Unit Overview Facts: Report - Test Steelut Facts: Report - Test Yield Facts: Report - Test Step Yield Facts: Report - Test Step Firor Pareto Facts: Report - Test Step Duration Facts: Report - Test Step Duration Facts: Report - Test Duration Facts: Report - Test Duration Facts: Report - Rest Duration Facts: Report - Rest Duration Facts: Report - Kepair Pareto Facts: Report - XY Graph Facts: Report - Audio Graph Facts: Dashboard Facts: Dashboard Facts: Dashboard	

8 Statistical calculations

In the SPC report, a number of statistical values are calculated and used for presentation. This section shows the formulas used to calculate these values. The formulas are shown for reference only. Please refer to special articles and literature regarding the practical use and limitations of the calculated values.

In the formulas below, USL and LSL denotes the upper specification limit and the lower specification limit.

8.1 Formulas

8.1.1 Mean value (\overline{X})

$$Mean = \bar{X} = \frac{1}{n} \sum_{i=1}^{i=n} X_i$$

8.1.2 Standard deviation (σ)

$$\sigma = \sqrt{\frac{1}{n-1} \sum_{i=1}^{i=n} (X_i - \bar{X})^2}$$



8.1.3 Capability (Cp)

$$C_p = \frac{USL - LSL}{6\sigma}$$

8.1.4 Capability Index (Cpk)

$$C_{pk}USL = \frac{USL - \bar{X}}{3\sigma}$$

$$C_{pk}LSL = \frac{\bar{X} - LSL}{3\sigma}$$

$$C_{pk} = \frac{Min[(USL - \bar{X}), (\bar{X} - LSL)]}{3\sigma} = Min[(C_{pk}USL), (C_{pk}LSL)]$$

8.2 Special value handling

In order to avoid misleading values for any of the capability values (Cp, Cpk, Cpk USL and Cpk LSL) in case of special circumstances in the test data, a special "error value" is used. In case any of the mentioned capability values are less than -999.999 or greater than 999.999, the resulting value will be set to -999.999 or 999.999 respectively.



9 Revision History

Revision	Date	Initials	Description
0.1	2013-04-29	LDI	First version
1.0	2013-05-01	LDI, RD	Review
1.1	2013-05-23	PCL	Dashboard minimum number of tests
1.2	2013-12-17	RD	Updated screen shots and filter options availability (most pages)
1.3	2014-05-11	PCL	Removed obsolete Test completion filter and added Test
			categories filter.
1.4	2016-05-20	KIP	Added information on Alarm Service, distribution groups, panel
			config and dashboard configurations.
1.4.1	2016-06-02	KIP	Updated images; renamed CPT to FACTS
1.4.2	2017-08-03	KIP	Added new Widgets
1.4.3	2018-08-12	RBN	Added Gauge R&R